## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE BEFORE THE PATENT TRIAL AND APPEAL BOARD

IPR2023-01382

**CERTIFIED COPY** 

U.S. Patent No. 9,748,347

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INNOSCIENCE (ZHUHAI) TECHNOLOGY COMPANY, LTD. and INNOSCIENCE AMERICA, INC.,

Petitioners,

v.

EFFICIENT POWER CONVERSION CORPORATION,
Patent Owner.

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ORAL DEPOSITION OF JAMES RICHARD SHEALY, PH.D.

Thursday, May 16, 2024

Reported by:

SUSAN ASHE, Certified Electronic Reporter

Job No.: 137277



| 1  | IN THE UNITED STATES PATENT AND TRADEMARK OFFICE  |
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| 2  | BEFORE THE PATENT TRIAL AND APPEAL BOARD          |
| 3  |   |
| 4  | IPR2023-01382 CERTIFIED COPY                      |
| 5  | U.S. Patent No. 9,748,347                         |
| 6  |   |
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| 8  | INNOSCIENCE (ZHUHAI) TECHNOLOGY COMPANY, LTD. and |
| 9  | INNOSCIENCE AMERICA, INC.,                        |
| 10 | Petitioners,                                      |
| 11 | v.  |
| 12 | EFFICIENT POWER CONVERSION CORPORATION,           |
| 13 | Patent Owner.                                     |
| 14 |   |
| 15 |   |
| 16 | ORAL DEPOSITION OF JAMES RICHARD SHEALY, PH.D.    |
| 17 |   |
| 18 | Thursday, May 16, 2024                            |
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| 23 | Reported by:                                      |
| 24 | SUSAN ASHE, Certified Electronic Reporter         |
| 25 | Job No.: 137277                                   |
|    |   |

| 1  | IN THE UNITED STATES PATENT AND TRADEMARK OFFICE     |
|----|--|
| 2  | BEFORE THE PATENT TRIAL AND APPEAL BOARD             |
| 3  |  |
| 4  | IPR2023-01384  |
| 5  | U.S. Patent No. 10,312,335                           |
| 6  |  |
| 7  |  |
| 8  | INNOSCIENCE (ZHUHAI) TECHNOLOGY COMPANY, LTD. and    |
| 9  | INNOSCIENCE AMERICA, INC.,                           |
| 10 | Petitioners,   |
| 11 | v.   |
| 12 | EFFICIENT POWER CONVERSION CORPORATION,              |
| 13 | Patent Owner.  |
| 14 |  |
| 15 |  |
| 16 |  |
| 17 | Oral deposition of JAMES RICHARD SHEALY,             |
| 18 | PH.D., taken on behalf of the Petitioners, beginning |
| 19 | at 9:03 a.m., on Thursday, May 16, 2024, at the law  |
| 20 | offices of Finnegan, Henderson, Farabow, Garrett &   |
| 21 | Dunner, LLP, 1875 Explorer~Street, Reston, Virginia, |
| 22 | before Susan Ashe, Certified Electronic Reporter,    |
| 23 | and Notary Public of the Commonwealth of Virginia.   |
| 24 |  |
| 25 |  |

| 1  | APPEARANCE OF COUNSEL:        |
|----|-------------------------------|
| 2  | On behalf of the Petitioners: |
| 3  | BLANK ROME LLP                |
| 4  | BY: DIPU A. DOSHI, ESQ.       |
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| 14 |                               |
| 15 |                               |
| 16 |                               |
| 17 |                               |
| 18 |                               |
| 19 |                               |
| 20 |                               |
| 21 |                               |
| 22 |                               |
| 23 |                               |
| 24 |                               |
| 25 |                               |

| 1  | APPEARANCE OF COUNSEL (Continued):              |
|----|---|
| 2  | On behalf of the Patent Holder and the Witness: |
| 3  | FINNEGAN, HENDERSON, FARABOW, GARRETT &         |
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| 19 |   |
| 20 | ALSO PRESENT:                                   |
| 21 | Caitlin Coverstone, Patent Agent                |
| 22 | Finnegan, Henderson, Farabow, Garrett &         |
| 23 | Dunner, LLP                                     |
| 24 |   |
| 25 |   |

| 1  |               | CONTENTS                      |        |
|----|---------------|-------------------------------|--------|
| 2  | THE WITNESS   |                               |        |
| 3  | James Richard | Shealy, Ph.D.                 |        |
| 4  |               |                               |        |
| 5  | BY MR. DOSH   | I                             | 7, 106 |
| 6  | BY MS. SPEC   | HT                            | 96     |
| 7  |               |                               |        |
| 8  |               | EXHIBITS                      |        |
| 9  | Exhibit No.   |                               | Marked |
| 10 | Exhibit 1032  | Hand Drawing "low drain bias" | 105    |
| 11 | Exhibit 2001  | Patent Owner's Notice of      |        |
| 12 |               | Deposition of                 |        |
| 13 |               | Dr. James Shealy              |        |
| 14 |               | U.S. Patent No. 9,748,347     | 11     |
| 15 | Exhibit 2001  | Patent Owner's Notice of      |        |
| 16 |               | Deposition of                 |        |
| 17 |               | Dr. James Shealy              |        |
| 18 |               | U.S. Patent No. 10,312,335    | 11     |
| 19 | Exhibit 2002  | Hand Drawing "photoresist"    | 49     |
| 20 | Exhibit 2003  | Hand Drawing "low drain bias" | 69     |
| 21 |               |                               |        |
| 22 |               |                               |        |
| 23 |               |                               |        |
| 24 |               |                               |        |
| 25 |               |                               |        |
|    |               |                               |        |

| 1  |         |      | PREVIOUSLY MARKED EXHIBITS   |            |
|----|---------|------|------------------------------|------------|
| 2  | Exhibit | No.  |                              | Introduced |
| 3  | Exhibit | 1003 | Declaration of               |            |
| 4  |         |      | James Richard Shealy, Ph.D.  | 12         |
| 5  | Exhibit | 1006 | "Yoshida Reference"          | 74         |
| 6  | Exhibit | 1007 | U.S. Patent Application      |            |
| 7  |         |      | 2006/0108606                 | 28         |
| 8  | Exhibit | 1008 | U.S. Patent Application      |            |
| 9  |         |      | 2007/0007547                 | 86         |
| 10 | Exhibit | 1009 | "Shenoy Reference" Journal o | of         |
| 11 |         |      | the Electrochemical Society  | 91         |
| 12 | Exhibit | 1020 | "Uemoto Reference"           | 93         |
| 13 | Exhibit | 1021 | U.S. Patent Application      |            |
| 14 |         |      | 2006/0019435                 | 85         |
| 15 |         |      |                              |            |
| 16 |         |      |                              |            |
| 17 |         |      |                              |            |
| 18 |         |      |                              |            |
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|-------|----|--|
|       | 1  | THURSDAY, MAY 16, 2024;                    |
|       | 2  | 9:03 A.M. EASTERN DAYLIGHT TIME            |
|       | 3  | 000  |
|       | 4  | Whereupon,                                 |
|       | 5  | JAMES RICHARD SHEALY, PH.D.                |
|       | 6  | having been first duly sworn, was examined |
|       | 7  | and testified as follows:                  |
|       | 8  | MR. DOSHI: Dipu Doshi, for                 |
|       | 9  | Efficient Power Conversion Corporation,    |
| 09:03 | 10 | from Blank Rome.                           |
|       | 11 | Also with me are Mark Mashack              |
|       | 12 | and Ameya Paradkar.                        |
|       | 13 | MS. SPECHT: And Kara Specht,               |
|       | 14 | from Finnegan, for Innoscience, the        |
| 09:04 | 15 | petitioner.                                |
|       | 16 | And with me is Dr. Luke                    |
|       | 17 | MacDonald, Lionel Lavenue, Caitlin         |
|       | 18 | Coverstone also from Finnegan.             |
|       | 19 | EXAMINATION                                |
| 09:04 | 20 | BY MR. DOSHI:                              |
|       | 21 | Q. Good morning, Dr. Shealy.               |
|       | 22 | A. Good morning.                           |
|       | 23 | Q. How are you?                            |
|       | 24 | A. Fine, thanks.                           |
| 09:04 | 25 | Q. Okay. You've been deposed before?       |
|       |    |  |

| 09:04 | 1  | A. Yes.   |
|-------|----|---|
|       | 2  | Q. And so, I'll just give you the short             |
|       | 3  | version of the ground rules, which are that the     |
|       | 4  | court reporter, or something, is taking all of the  |
| 09:04 | 5  | words that we're saying today down. So it's         |
|       | 6  | important that we not talk over one another. Okay?  |
|       | 7  | And I'm going to try to break every 45 to           |
|       | 8  | 60 minutes. If you need a break before that time,   |
|       | 9  | just let me know and we'll break. But I just ask    |
| 09:04 | 10 | that if there's a pending question, that you answer |
|       | 11 | the question before.                                |
|       | 12 | And then I think                                    |
|       | 13 | That's the short version                            |
|       | 14 | A. Okay.  |
| 09:04 | 15 | Q of the ground rules.                              |
|       | 16 | If anything else comes up, let me know.             |
|       | 17 | A. Okay.  |
|       | 18 | Q. All right. So what did you do to prepare         |
|       | 19 | for today's deposition?                             |
| 09:05 | 20 | A. Okay. I got these binders in the mail            |
|       | 21 | about two weeks ago maybe two and a half weeks      |
|       | 22 | ago, I think.                                       |
|       | 23 | And then about a week ago, we had two               |
|       | 24 | Zoom, like, prep sessions with these three lawyers  |
| 09:05 | 25 | here.   |

| 09:05 | 1  | And then we had, the day before yesterday        |
|-------|----|--|
|       | 2  | and yesterday, in-office prep session.           |
|       | 3  | Q. Great. And did you speak with anyone          |
|       | 4  | other than the Finnegan lawyers in preparing for |
| 09:06 | 5  | today's deposition?                              |
|       | 6  | A. No.   |
|       | 7  | Q. Did you review documents, other than those    |
|       | 8  | that you said were shipped to you?               |
|       | 9  | A. There's two binders for each patent one       |
| 09:06 | 10 | exhibits, one pleadings.                         |
|       | 11 | So, I've looked at those.                        |
|       | 12 | Q. Okay.   |
|       | 13 | A. And that's all I've looked at.                |
|       | 14 | Q. Okay. And just to be clear, you said "the     |
| 09:06 | 15 | two patents."                                    |
|       | 16 | So it's your understanding that we're            |
|       | 17 | talking about the '347 and '335 patents today?   |
|       | 18 | A. Yes.  |
|       | 19 | Q. Okay. And so for the record, I'll say         |
| 09:06 | 20 | that the '347 patent is 9,748,347.               |
|       | 21 | Is that your understanding?                      |
|       | 22 | A. That's correct.                               |
|       | 23 | Q. And that is for IPR2023-01382.                |
|       | 24 | Is that correct?                                 |
| 09:06 | 25 | A. That's correct.                               |

| 09:06 | 1  | Q. All right. And the '335 patent, the full    |
|-------|----|--|
|       | 2  | number for that is 10,312,335.                 |
|       | 3  | Do you agree?                                  |
|       | 4  | A. Yes.  |
| 09:07 | 5  | Q. All right. And that is for IPR2023-01384.   |
|       | 6  | Correct?                                       |
|       | 7  | A. Yes.  |
|       | 8  | Q. Okay, great.                                |
|       | 9  | All right. So you have authored a total        |
| 09:07 | 10 | of four declarations for four patents that are |
|       | 11 | assigned to EPC. Correct?                      |
|       | 12 | A. Yes. But I've only reviewed these two for   |
|       | 13 | today.   |
|       | 14 | Q. Understood. That's great.                   |
| 09:07 | 15 | MR. DOSHI: Okay. So I'm going                  |
|       | 16 | to hand you this is more of a formality        |
|       | 17 | than anything else and just for the            |
|       | 18 | record a notice of deposition of               |
|       | 19 | Dr. James Shealy.                              |
| 09:07 | 20 | So we'll mark this as                          |
|       | 21 | (Pause.)                                       |
|       | 22 | MR. DOSHI: Bear with us.                       |
|       | 23 | THE WITNESS: Sure.                             |
|       | 24 | (Pause.)                                       |
| 09:07 | 25 | MR. DOSHI: So we'll go with                    |
|       |    |  |

|       | 1  |  |
|-------|----|--|
| 09:07 | 1  | 2001.  |
|       | 2  | (Whereupon, Exhibit 2001 was marked for      |
|       | 3  | identification.)                             |
|       | 4  | MR. DOSHI: And that's 1382,                  |
| 09:09 | 5  | 2001 so, it's complicated.                   |
|       | 6  | And I'm handing you what's going             |
|       | 7  | to be also 2001 for 1384, a notice of        |
|       | 8  | deposition.                                  |
|       | 9  | COURT REPORTER: It's 2001                    |
| 09:09 | 10 | again?                                       |
|       | 11 | MR. DOSHI: Yeah I know, it's                 |
|       | 12 | complicated.                                 |
|       | 13 | (Whereupon, Exhibit 2001 was marked for      |
|       | 14 | identification.)                             |
| 10:25 | 15 | BY MR. DOSHI:                                |
|       | 16 | Q. And again, this is more for formalities   |
|       | 17 | than anything else.                          |
|       | 18 | A. Okay.                                     |
|       | 19 | Q. And have you seen these documents before, |
| 09:10 | 20 | the ones I just handed you 2001, 1382?       |
|       | 21 | A. I don't I don't recall. I might have      |
|       | 22 | received them in an email or something. But  |
|       | 23 | MR. DOSHI: Okay. Let me hand                 |
|       | 24 | you what has previously been marked as       |
| 09:10 | 25 | 1003, Exhibit 1003 in the 1382 proceeding.   |
|       |    |  |

| 09:10 | 1  | (Whereupon, Exhibit 1003, previously           |
|-------|----|--|
|       | 2  | marked, was presented to the witness.)         |
|       | 3  | BY MR. DOSHI:                                  |
|       | 4  | Q. Do you recognize that document?             |
| 09:11 | 5  | A. Yes.  |
|       | 6  | Q. Okay. And that is what?                     |
|       | 7  | A. That's my declaration for the '347 patent.  |
|       | 8  | Q. And I'm handing you 1384, what's been       |
|       | 9  | marked as 1003.                                |
| 09:11 | 10 | It's been previously marked, so you don't      |
|       | 11 | have to mark it.                               |
|       | 12 | Do you recognize that document?                |
|       | 13 | A. Yes.  |
|       | 14 | Q. And what do you recognize that to be?       |
| 09:11 | 15 | A. That's my declaration for the '335 patent.  |
|       | 16 | Q. Okay. So those two declarations are         |
|       | 17 | documents that you reviewed in preparation for |
|       | 18 | today's deposition?                            |
|       | 19 | A. Yes.  |
| 09:12 | 20 | Q. Okay. And do you have your own you          |
|       | 21 | have your own copy?                            |
|       | 22 | A. Yes.  |
|       | 23 | Q. Okay. That has notes and stuff in there?    |
|       | 24 | A. No; no notes.                               |
| 09:12 | 25 | Q. Okay. And you can use your own copy if it   |
|       |    |  |

| 09:12 | 1  | has no notes in it.                                  |
|-------|----|--|
|       | 2  | A. No; there's no notes.                             |
|       | 3  | Q. Okay. If you're comfortable with that.            |
|       | 4  | So the declarations that I've handed you             |
| 09:12 | 5  | have your opinions on the validity of the two        |
|       | 6  | patents. Correct?                                    |
|       | 7  | A. Correct.  |
|       | 8  | Q. In formulating your opinions, did you             |
|       | 9  | speak with anyone outside of the Finnegan attorneys? |
| 09:12 | 10 | A. No.   |
|       | 11 | Q. Okay. Other than the documents that you           |
|       | 12 | cite in your reports for your declarations, did you  |
|       | 13 | review any other documents?                          |
|       | 14 | A. Yes.  |
| 09:13 | 15 | Q. Okay. And do you recall what those                |
|       | 16 | documents were?                                      |
|       | 17 | A. The patent owner response, the Board              |
|       | 18 | decisions and, you know, all the references.         |
|       | 19 | I'm trying to think if I'm forgetting                |
| 09:13 | 20 | anything. Let me look                                |
|       | 21 | We have all the pleadings for each case.             |
|       | 22 | And so, there's so I've looked at all                |
|       | 23 | of these: the petition, the patent owner response,   |
|       | 24 | the petitioner preliminary reply, the patent owner   |
| 09:14 | 25 | sur reply, and then the institution decision.        |

| 09:14 | 1  | So I looked at all of those for each                |
|-------|----|---|
|       | 2  | patent.   |
|       | 3  | Q. Have you spoken with anyone about the            |
|       | 4  | ongoing litigation between EPC and Innoscience?     |
| 09:14 | 5  | A. No well, other than this case.                   |
|       | 6  | I mean, I don't know if this is considered          |
|       | 7  | a litigation, but                                   |
|       | 8  | It is, isn't it?                                    |
|       | 9  | Q. Sure.  |
| 09:14 | 10 | A. Yeah.  |
|       | 11 | Q. How did you come about being an expert for       |
|       | 12 | Innoscience?  |
|       | 13 | A. I think I was contacted. I don't remember        |
|       | 14 | by who, but one of the attorneys.                   |
| 09:14 | 15 | And I had done work for Finnegan before.            |
|       | 16 | I don't know if that had any bearing on it.         |
|       | 17 | But they contacted me and we discussed it.          |
|       | 18 | And then we decided I would be the expert in these. |
|       | 19 | Q. Okay. And do you recall when you were            |
| 09:15 | 20 | contacted by Finnegan?                              |
|       | 21 | A. It's been a while. So I can't really give        |
|       | 22 | you an accurate date. But                           |
|       | 23 | Q. 2023?  |
|       | 24 | A. I would say something on the order of a          |
| 09:15 | 25 | year ago, maybe is my guess.                        |

| 09:15 | 1  | Q. Spring 2023?                                     |
|-------|----|---|
|       | 2  | A. Something like that, yeah.                       |
|       | 3  | Q. Okay. In Paragraph 3 of your declaration         |
|       | 4  | for the '347, you say that you're being compensated |
| 09:15 | 5  | for your time at your standard hourly consulting    |
|       | 6  | rate.   |
|       | 7  | What is your consulting rate?                       |
|       | 8  | A. Yes, I see that. 750 an hour.                    |
|       | 9  | Q. Okay. And you state that you have no             |
| 09:15 | 10 | other interest in this proceeding.                  |
|       | 11 | Is that correct?                                    |
|       | 12 | A. No I mean, what do you mean? "No                 |
|       | 13 | interest"?  |
|       | 14 | Q. It's on Paragraph 3 so, if you can look          |
| 09:16 | 15 | at Paragraph 3, the last part of that sentence, the |
|       | 16 | last sentence.                                      |
|       | 17 | A. No. I have no other interest in this             |
|       | 18 | proceeding.   |
|       | 19 | Q. Okay. Other than publicly available prior        |
| 09:16 | 20 | art and the documents you discussed, did counsel    |
|       | 21 | provide you with any material any other material    |
|       | 22 | from the  |
|       | 23 | Well, let me back up.                               |
|       | 24 | Do you understand that there is a pending           |
| 09:16 | 25 | ITC investigation between EPC and Innoscience?      |

| 09:16 | 1  | A. Yes.   |
|-------|----|---|
|       | 2  | Q. Okay. Did counsel provide you with any of        |
|       | 3  | the documents from that investigation?              |
|       | 4  | A. No.  |
| 09:16 | 5  | Q. Okay. Have you had discussions with              |
|       | 6  | Dr. Levy?   |
|       | 7  | A. No.  |
|       | 8  | Q. Okay. Do you know who Dr. Levy is?               |
|       | 9  | A. Not really.                                      |
| 09:17 | 10 | Q. Okay. Dr. Levy                                   |
|       | 11 | A. Georgia Tech, was it? Or                         |
|       | 12 | Q. That's a good question. I don't know.            |
|       | 13 | Do you know if Innoscience has another              |
|       | 14 | expert that opined on invalidity in connection with |
| 09:17 | 15 | the ITC investigation?                              |
|       | 16 | A. I don't know who it is, and I have no            |
|       | 17 | information on that. So                             |
|       | 18 | Q. Okay. Were you provided with any                 |
|       | 19 | deposition transcripts to review in                 |
| 09:17 | 20 | A. No.  |
|       | 21 | Q. Any emails from Dr. Levy?                        |
|       | 22 | A. No.  |
|       | 23 | Q. Any hearing transcripts?                         |
|       | 24 | A. No.  |
| 09:17 | 25 | Q. Did you discuss your I think I asked             |
|       |    | l l   |

| 09:18 | 1  | this, but I'm going to phrase it a little        |
|-------|----|--|
|       | 2  | differently.                                     |
|       | 3  | Did you discuss your involvement in              |
|       | 4  | this in these proceedings with anyone outside of |
| 09:18 | 5  | your lawyers?                                    |
|       | 6  | A. No.   |
|       | 7  | Q. Did you speak with some of your colleagues    |
|       | 8  | at work about this?                              |
|       | 9  | A. No.   |
| 09:18 | 10 | Q. Did you inform them of your involvement in    |
|       | 11 | this case?                                       |
|       | 12 | And let me clear that up.                        |
|       | 13 | Have you informed your colleagues of your        |
|       | 14 | involvement in this case?                        |
| 09:18 | 15 | A. No. They know I'm out of town for a week.     |
|       | 16 | But other than that, no.                         |
|       | 17 | Q. All right. Let's turn to Paragraph 19         |
|       | 18 | of   |
|       | 19 | A. Where, the '347?                              |
| 09:18 | 20 | Q. '347.   |
|       | 21 | In 2019, you co-founded Odyssey                  |
|       | 22 | Semiconductor. Correct?                          |
|       | 23 | A. Where did you say?                            |
|       | 24 | Q. I'm sorry. Paragraph 19. Page 5.              |
| 09:19 | 25 | A. Oh, Paragraph 19. Okay.                       |

| 09:19 | 1  | (Pause.)  |
|-------|----|---|
|       | 2  | A. Okay.  |
|       | 3  | Q. In Paragraph 19, you quote you say,              |
|       | 4  | quote:  |
| 09:19 | 5  | I co-founded Odyssey                                |
|       | 6  | Semiconductor, end quote.                           |
|       | 7  | Do you see that?                                    |
|       | 8  | A. Yes.   |
|       | 9  | Q. What is the business of Odyssey                  |
| 09:19 | 10 | Semiconductor?                                      |
|       | 11 | A. Odyssey Semiconductor is engaged in              |
|       | 12 | designing and building prototypes of vertical       |
|       | 13 | high-power gallium nitride transistors.             |
|       | 14 | Q. Okay. Can you elaborate on what the              |
| 09:20 | 15 | day-to-day operations of Odyssey Semiconductor are? |
|       | 16 | A. We have a semiconductor fab. So we               |
|       | 17 | take we do not produce gallium nitride epitaxy.     |
|       | 18 | So we procure that.                                 |
|       | 19 | And we conduct semiconductor processes to           |
| 09:20 | 20 | create vertical FETs in that host material.         |
|       | 21 | And so, those devices involve plasma                |
|       | 22 | etching, several types of plasma etching, metal     |
|       | 23 | deposition, dielectric deposition you know, all     |
|       | 24 | of the photolithography everything you associate    |
| 09:21 | 25 | with building a gallium nitride device.             |

| 09:21 | 1  | It's not the same device, as these are               |
|-------|----|--|
|       | 2  | lateral conduction devices.                          |
|       | 3  | So vertical conduction is a totally                  |
|       | 4  | different animal, but it uses a lot of the same      |
| 09:21 | 5  | fabrication techniques.                              |
|       | 6  | Q. Understood.                                       |
|       | 7  | And when you say it's not the same as                |
|       | 8  | these, you're pointing to the patents?               |
|       | 9  | A. Yes. These are these two patents                  |
| 09:21 | 10 | and all of the prior art references all describe     |
|       | 11 | well, not all the prior art, but much much of the    |
|       | 12 | prior art describes lateral conduction Field Effect  |
|       | 13 | Transistors. And they're often referred to as        |
|       | 14 | "HEMTs."   |
| 09:22 | 15 | I used to build HEMTs at Cornell back in             |
|       | 16 | the late '90s.                                       |
|       | 17 | We built the first gallium nitride HEMT on           |
|       | 18 | silicon, which is the basis for all of this          |
|       | 19 | technology.  |
| 09:22 | 20 | We were also the first to build an                   |
|       | 21 | insulated gate transistor on gallium nitride. And    |
|       | 22 | we developed nucleation methods, which are appear    |
|       | 23 | to be dominating the you have to nucleate these      |
|       | 24 | materials when you grow them on silicon or sapphire, |
| 09:22 | 25 | a different semiconductor substrate.                 |

| 09:22 | 1  | And so, we've we were the first                     |
|-------|----|---|
|       | 2  | well, "first" we Nakamura came up with a            |
|       | 3  | nucleation method. That's what the world used.      |
|       | 4  | We came up with one in the mid '90s which           |
| 09:23 | 5  | replaced that and works better, and now that's      |
|       | 6  | heavily in use. And that's also patented.           |
|       | 7  | Q. Okay. Thank you.                                 |
|       | 8  | Going back to Odyssey, you say that the             |
|       | 9  | you don't do Odyssey doesn't have its own epi.      |
| 09:23 | 10 | A. That's correct.                                  |
|       | 11 | Q. Okay. So when we say "epi," we're talking        |
|       | 12 | about the growth of the layers up to what level?    |
|       | 13 | A. Well, the epitaxial structure for a              |
|       | 14 | vertical device is obviously different than a HEMT. |
| 09:23 | 15 | But so the vertical device would                    |
|       | 16 | typically have three to five layers in it, and      |
|       | 17 | they're all gallium nitride, and they're all doped  |
|       | 18 | n-type.   |
|       | 19 | Q. Okay. And where does Odyssey                     |
| 09:23 | 20 | Semiconductor source that material from?            |
|       | 21 | A. We've sourced it from a lot of places.           |
|       | 22 | But, currently, we're collaborating with            |
|       | 23 | Sandia Labs, and they're providing us all the       |
|       | 24 | epitaxial material there.                           |
| 09:24 | 25 | They're actually experts. They've been at           |

| 09:24 | 1  | it a long time as have I. I mean, when I was at |
|-------|----|---|
|       | 2  | Cornell, we my group designed and built MOCVD   |
|       | 3  | reactors to grow gallium nitride.               |
|       | 4  | So I've been involved in the heavily            |
| 09:24 | 5  | involved in the epitaxy end of things.          |
|       | 6  | Q. Has Odyssey Semiconductors sourced any       |
|       | 7  | material from Innoscience?                      |
|       | 8  | A. No.  |
|       | 9  | (Pause.)  |
| 09:24 | 10 | A. Maybe I should have said: The vertical       |
|       | 11 | transistors are grown on a gallium nitride      |
|       | 12 | substrate.                                      |
|       | 13 | And as far as I know, neither one of these      |
|       | 14 | parties involved here work with gallium nitride |
| 09:25 | 15 | substrates.                                     |
|       | 16 | So it's a single crystal, low-defect            |
|       | 17 | density sort of arrangement.                    |
|       | 18 | Q. And that would be the substrate?             |
|       | 19 | A. The substrate is low-defect density. We      |
| 09:25 | 20 | source those from Japan.                        |
|       | 21 | But the it's also a conducting                  |
|       | 22 | substrate. And when you're doing HEMTs, you're  |
|       | 23 | looking for an insulating substrate, generally. |
|       | 24 | So there's a lot of differences, right          |
| 09:25 | 25 | from the substrate all the way up.              |

| 09:25 | 1  | Q. And you say in Paragraph 19 on Page 5             |
|-------|----|--|
|       | 2  | that:  |
|       | 3  | Odyssey Semiconductor also                           |
|       | 4  | recently developed the                               |
| 09:25 | 5  | fabrication techniques.                              |
|       | 6  | How recently did Odyssey Semiconductor               |
|       | 7  | develop the fabrication techniques?                  |
|       | 8  | A. This is referring to micro-LED arrays.            |
|       | 9  | To help pay the bills, we do foundry work            |
| 09:26 | 10 | because we have a fab.                               |
|       | 11 | So there's two or three companies that               |
|       | 12 | have approached us, and we've done micro-LED work    |
|       | 13 | for two companies.                                   |
|       | 14 | So that also involved a lot of the same              |
| 09:26 | 15 | core sets of gallium nitride-based Light Emitting    |
|       | 16 | Diode. And a lot of the same fabrication techniques  |
|       | 17 | that were used there are also used kind of generally |
|       | 18 | to process gallium nitride and related materials.    |
|       | 19 | Q. Where are Odyssey Semiconductor's fabs            |
| 09:26 | 20 | located?   |
|       | 21 | A. There's only one fab. It's in Ithaca, New         |
|       | 22 | York at the airport.                                 |
|       | 23 | Q. Let's go back to your                             |
|       | 24 | How many times have you been deposed?                |
| 09:27 | 25 | A. I don't know. Somewhere between, I'd say,         |

| 09:27 | 1  | ten and twenty times.                             |
|-------|----|---|
|       | 2  | Q. Have you testified at trial?                   |
|       | 3  | A. Do you consider ITC trials?                    |
|       | 4  | Q. Sure.  |
| 09:27 | 5  | A. I've done, I think, three ITC trials.          |
|       | 6  | I've only done one district court trial in        |
|       | 7  | front of a live jury.                             |
|       | 8  | Q. Okay.  |
|       | 9  | A. ButI think that covers it.                     |
| 09:27 | 10 | Q. Okay. Do you know Dr. Schubert?                |
|       | 11 | A. Yes.   |
|       | 12 | Q. How do you know him?                           |
|       | 13 | A. I've known him a long time.                    |
|       | 14 | Back when he was at Bell Labs is when I           |
| 09:27 | 15 | first met him. He used to come up and visit us at |
|       | 16 | Cornell.  |
|       | 17 | But I was his expert when he was going            |
|       | 18 | around litigating his patent. So I know him from  |
|       | 19 | that as well.                                     |
| 09:28 | 20 | Q. You said you've testified at a jury trial.     |
|       | 21 | What did that trial involve?                      |
|       | 22 | A. That involved Light Emitting Diodes used       |
|       | 23 | for, you know, commercial lighting lamps.         |
|       | 24 | Q. Okay. And then the three ITC trials, what      |
| 09:28 | 25 | did those involve?                                |

| 09:28 | 1  | A. The first one involvedthe                     |
|-------|----|--|
|       | 2  | All right. Now you're taking me back a           |
|       | 3  | decade or so.                                    |
|       | 4  | Q. To the best of your recollection.             |
| 09:29 | 5  | A. The first one involved a patent that I        |
|       | 6  | can't even remember the                          |
|       | 7  | The patent involved gallium nitride              |
|       | 8  | materials, in general.                           |
|       | 9  | And the other ITC trial was a involved           |
| 09:29 | 10 | Light Emitting Diodes again.                     |
|       | 11 | And that, I think                                |
|       | 12 | And then, the last ITC trial I did was           |
|       | 13 | involving the electronic circuits to drive LEDs. |
|       | 14 | Q. Have you worked with EPC at all?              |
| 09:30 | 15 | A. No. I discussed working with them, but I      |
|       | 16 | never have worked for them.                      |
|       | 17 | Q. Do you know Alex Lidow?                       |
|       | 18 | A. No.   |
|       | 19 | Q. Do you know any of the inventors on the       |
| 09:30 | 20 | '347 patent?                                     |
|       | 21 | A. No.   |
|       | 22 | Q. Okay. Earlier, you said that you do           |
|       | 23 | foundry work because you have a fab.             |
|       | 24 | Is that right?                                   |
| 09:31 | 25 | A. Yes.  |
|       |    | l l  |

| 09:31 | 1  | Q. And there are two or three companies that        |
|-------|----|---|
|       | 2  | approached you.                                     |
|       | 3  | Is that right?                                      |
|       | 4  | A. There's been a lot of companies that have        |
| 09:31 | 5  | approached us.                                      |
|       | 6  | We've done a lot of fab work for a lot of           |
|       | 7  | different companies I just mentioned.               |
|       | 8  | I was responding to your question about             |
|       | 9  | the micro-LED arrays.                               |
| 09:31 | 10 | Q. Okay. What other companies have you done         |
|       | 11 | work for?   |
|       | 12 | A. There's a company called "Innovation." I         |
|       | 13 | don't know if there's anything beyond "Innovation." |
|       | 14 | That's what I call them.                            |
| 09:31 | 15 | They they're in I think they're                     |
|       | 16 | based in Rochester. And we've built micro-LED       |
|       | 17 | arrays for them.                                    |
|       | 18 | There was another Canadian company we did           |
|       | 19 | that for, and I VueReal, I think or VueReal,        |
| 09:32 | 20 | or something, was their name.                       |
|       | 21 | And then we've done a lot of odd jobs               |
|       | 22 | for you know, I'm not really involved in the        |
|       | 23 | foundry part of that. So                            |
|       | 24 | But thethere's a company in Buffalo                 |
| 09:32 | 25 | we're currently building some nuclear batteries,    |

| 09:32 | 1  | using GaN.  |
|-------|----|---|
|       | 2  | And then there's many others I just can't           |
|       | 3  | remember.   |
|       | 4  | Q. Do any of the companies design gallium           |
| 09:32 | 5  | nitride transistors?                                |
|       | 6  | A. I think we've done one job involving HEMTs       |
|       | 7  | and gallium nitride, yeah.                          |
|       | 8  | Q. Can you tell me any details about that           |
|       | 9  | job?  |
| 09:33 | 10 | A. We just there was a company interested           |
|       | 11 | in integrating HEMTs with another device.           |
|       | 12 | And so, we they provided us with some               |
|       | 13 | substrates. And HEMTs are, by comparison, much      |
|       | 14 | easier to fabricate than a vertical GaN transistor. |
| 09:33 | 15 | And so, we just built some standard HEMTs           |
|       | 16 | for them, using, more or less, the techniques       |
|       | 17 | that we kind of imported the technology from        |
|       | 18 | Cornell, obviously, into this company. So we have   |
|       | 19 | certain ways of building HEMTs.                     |
| 09:33 | 20 | And so, we've carried that those out.               |
|       | 21 | Q. Okay. And which company was that?                |
|       | 22 | A. I can't tell you off the top of my head.         |
|       | 23 | It wasn't a big HEMT company like the two           |
|       | 24 | players here.                                       |
| 09:34 | 25 | It was a small company. I just don't                |

| 09:34 | 1  | remember the name.                                  |
|-------|----|---|
|       | 2  | Q. Have you had discussions with any                |
|       | 3  | Innoscience employees in formulating your opinions? |
|       | 4  | A. No.  |
| 09:35 | 5  | Q. So it was just the one company that you          |
|       | 6  | were focused on making HEMTs for?                   |
|       | 7  | A. Yeah, it was                                     |
|       | 8  | Like, you know, we built them, tested               |
|       | 9  | them, shipped them out. And that was the end of it. |
| 09:35 | 10 | Q. And that was in your fab in New York?            |
|       | 11 | A. That's correct.                                  |
|       | 12 | Q. And the way that works is that epitaxial         |
|       | 13 | layers are sourced from somewhere and then shipped  |
|       | 14 | to your fab?  |
| 09:35 | 15 | A. Yes.   |
|       | 16 | Q. Do you know where those epitaxial layers         |
|       | 17 | were shipped from?                                  |
|       | 18 | A. No. I don't remember the details of the          |
|       | 19 | job. I just know that the job did happen, because I |
| 09:36 | 20 | was consulted on some of the fabrication issues on  |
|       | 21 | it.   |
|       | 22 | MR. DOSHI: Why don't we take a                      |
|       | 23 | short break   |
|       | 24 | THE WITNESS: Okay.                                  |
| 09:37 | 25 | MR. DOSHI: because I'm about                        |

|       | 1  |   |
|-------|----|---|
| 09:37 | 1  | to switch topics.                                 |
|       | 2  | Can we go off the record.                         |
|       | 3  | (Whereupon, a recess was taken                    |
|       | 4  | from 9:37 a.m. until 9:49 a.m.)                   |
| 09:49 | 5  | BY MR. DOSHI:                                     |
|       | 6  | Q. Dr. Shealy, welcome back.                      |
|       | 7  | A. Thank you.                                     |
|       | 8  | Q. Before the break, we were talking about        |
|       | 9  | HEMTs. And I just want to clarify for the record, |
| 09:49 | 10 | it's H-E-M-T. Correct?                            |
|       | 11 | A. High Electron Mobility Transistor, yeah.       |
|       | 12 | Q. Thank you.                                     |
|       | 13 | MR. DOSHI: All right. I'm                         |
|       | 14 | handing you what has previously been              |
| 09:49 | 15 | marked as 1007.                                   |
|       | 16 | So this is 1007 in both 1382 and                  |
|       | 17 | 1384.   |
|       | 18 | THE WITNESS: These aren't being                   |
|       | 19 | marked now?                                       |
| 09:49 | 20 | COURT REPORTER: They're                           |
|       | 21 | premarked.  |
|       | 22 | THE WITNESS: Oh.                                  |
|       | 23 | MR. DOSHI: They've been marked.                   |
|       | 24 | (Whereupon, Exhibit 1007, previously              |
| 09:49 | 25 | marked, was presented to the witness.)            |
|       |    |   |

|       | ı  |  |
|-------|----|--|
| 09:49 | 1  | THE WITNESS: Okay oh, yeah.                          |
|       | 2  | BY MR. DOSHI:  |
|       | 3  | Q. And do you recognize this document?               |
|       | 4  | A. Yes.  |
| 09:50 | 5  | Q. What do you recognize it to be?                   |
|       | 6  | A. Excuse me?  |
|       | 7  | Q. What do you recognize it to be?                   |
|       | 8  | A. This is a prior art reference authored by         |
|       | 9  | Saxler.  |
| 09:50 | 10 | Q. Okay. And you rely on this document in            |
|       | 11 | your opinions. Correct?                              |
|       | 12 | A. Yes.  |
|       | 13 | Q. Okay. Looking at Figure 1A of Saxler, it          |
|       | 14 | shows a transistor having a recessed gate structure. |
| 09:50 | 15 | Correct?   |
|       | 16 | A. Yes.  |
|       | 17 | Q. Okay. And then 1B shows a nonrecessed             |
|       | 18 | transistor.  |
|       | 19 | Is that right?                                       |
| 09:50 | 20 | A. 1B is some sort of idealized                      |
|       | 21 | Yes, it'scould you repeat that                       |
|       | 22 | question? Sorry.                                     |
|       | 23 | Q. Sure. 1B shows a let me try it again.             |
|       | 24 | 1B of Saxler shows a nonrecessed                     |
| 09:50 | 25 | transistor. Right?                                   |

| 09:51 | 1  | A. It shows a transistor where the gate isn't |
|-------|----|---|
|       | 2  | recessed.                                     |
|       | 3  | Q. Okay. And then, you said turning to        |
|       | 4  | Figures 2 and A 2A and 2B on the next page.   |
| 09:51 | 5  | Do you see that?                              |
|       | 6  | A. Yes.                                       |
|       | 7  | Q. Yeah. It seems like they reversed it.      |
|       | 8  | Right?  |
|       | 9  | A and B is now reversed. And it looks         |
| 09:51 | 10 | like 2A is the nonrecessed transistor. Right? |
|       | 11 | A. In that depiction, yes, the gate is not    |
|       | 12 | recessed.                                     |
|       | 13 | Q. And 2B is the recessed transistor?         |
|       | 14 | A. The gate is recessed into the barrier      |
| 09:51 | 15 | layer in 2B.                                  |
|       | 16 | Q. Into the barrier layer in 2B, yes okay.    |
|       | 17 | Thank you.                                    |
|       | 18 | And on Page 41 of your declaration so,        |
|       | 19 | let's go to your report here.                 |
| 09:51 | 20 | Sorry. I'm using things interchangeably.      |
|       | 21 | Do you want to refer to your declaration      |
|       | 22 | as a particular noun? Is there something      |
|       | 23 | A. Sure. Let's refer to the declaration,      |
|       | 24 | yeah.   |
| 09:52 | 25 | Q. Okay, declaration.                         |

| 09:52 | 1  | Page 41 of your declaration, you have an           |
|-------|----|--|
|       | 2  | illustration.                                      |
|       | 3  | Do you see that?                                   |
|       | 4  | A. Yes.  |
| 09:52 | 5  | Q. And what is that illustration?                  |
|       | 6  | A. That is an illustration of a nonrecessed        |
|       | 7  | gate.  |
|       | 8  | So you start with Figure 1A and you remove         |
|       | 9  | the gate recess. And that's what you get when you  |
| 09:52 | 10 | remove the gate recess and change nothing else.    |
|       | 11 | Q. Okay. And the modified structure is             |
|       | 12 | something you put together?                        |
|       | 13 | A. Yeah, it was my opinion to that's what          |
|       | 14 | it means to recess the gate or to remove the       |
| 09:53 | 15 | recess, leave everything else the same. Let's just |
|       | 16 | remove the recess.                                 |
|       | 17 | Q. And this illustration is not in Saxler.         |
|       | 18 | Correct?   |
|       | 19 | A. It's described in Paragraph 52, I think,        |
| 09:53 | 20 | pretty effectively, if you want to look at that.   |
|       | 21 | Q. We'll get there.                                |
|       | 22 | A. Okay.   |
|       | 23 | Q. What I'm asking is: This depiction is not       |
|       | 24 | from Saxler. Correct?                              |
| 09:53 | 25 | A. It's a modified version of a figure from        |

| 09:53 | 1  | Saxler.  |
|-------|----|--|
|       | 2  | Q. And you modified it. Right?                       |
|       | 3  | A. Yes.  |
|       | 4  |  |
| 00 50 |    | Q. And then, did you use Photoshop or how            |
| 09:53 | 5  | did you come about this?                             |
|       | 6  | A. I think I probably told somebody to modify        |
|       | 7  | it. Somebody else did it on the computer.            |
|       | 8  | Q. Okay. So we'll call                               |
|       | 9  | Okay. You say that in your                           |
| 09:53 | 10 | declaration, you say that the recess is optional.    |
|       | 11 | Right?   |
|       | 12 | A. Saxler says that again and again.                 |
|       | 13 | Q. Okay. And you cite to a couple of                 |
|       | 14 | paragraphs that you say support your conclusion that |
| 09:54 | 15 | it's optional. Right?                                |
|       | 16 | A. Yes.  |
|       | 17 | Q. And then one of them is the abstract.             |
|       | 18 | Right?   |
|       | 19 | (Witness reading.)                                   |
| 09:54 | 20 | A. I don't see any discussion of a gate              |
|       | 21 | recess in the abstract.                              |
|       | 22 | Q. Okay.   |
|       | 23 | A. There's an Ohmic contact without a                |
|       | 24 | recess   |
| 09:54 | 25 | Q. That's right.                                     |
|       |    |  |

|       | ĺ  |   |
|-------|----|---|
| 09:54 | 1  | A mentioned in the abstract.                |
|       | 2  | Q. Okay. And then, another Paragraph is 13. |
|       | 3  | You're looking at Paragraph 13.             |
|       | 4  | A. Yes.                                     |
| 09:55 | 5  | Q. And then, the first sentence says:       |
|       | 6  | In particular embodiments                   |
|       | 7  | of the present invention                    |
|       | 8  | without a gate recess                       |
|       | 9  | A. Wait a minute, where are we reading?     |
| 09:55 | 10 | Q. Paragraph 13 of Saxler.                  |
|       | 11 | A. Saxler?                                  |
|       | 12 | In other embodiments?                       |
|       | 13 | Q. In particular embodiments.               |
|       | 14 | A. My version of this says "in other        |
| 09:55 | 15 | embodiments."                               |
|       | 16 | Q. Oh, I'm sorry. It's line                 |
|       | 17 | Well, there are no lines.                   |
|       | 18 | It's the fifth line from the top:           |
|       | 19 | In particular                               |
| 09:55 | 20 | embodiments                                 |
|       | 21 | A. In that paragraph? Or the                |
|       | 22 | Q. Yeah, in Paragraph 13.                   |
|       | 23 | (Witness reading.)                          |
|       | 24 | A. Okay.                                    |
| 09:55 | 25 | Q. Okay. It says:                           |
|       |    |   |

| 09:55 | 1  | In particular embodiments                        |
|-------|----|--|
|       | 2  | of the present invention with a                  |
|       | 3  | gate recess, the doped region                    |
|       | 4  | extends into the cap layer from                  |
| 09:56 | 5  | about 30 angstroms to about                      |
|       | 6  | 5000 angstroms.                                  |
|       | 7  | Is that right?                                   |
|       | 8  | A. Yes.  |
|       | 9  | Q. Okay. And then, the sentence that             |
| 09:56 | 10 | follows well, actually, if you go up from there, |
|       | 11 | the second line from the top, it says:           |
|       | 12 | In particular embodiments                        |
|       | 13 | of the present invention                         |
|       | 14 | without a gate recess, the                       |
| 09:56 | 15 | doped region extends into the                    |
|       | 16 | cap layer from about 2.5                         |
|       | 17 | angstroms to about                               |
|       | 18 | 15 angstroms.                                    |
|       | 19 | Do you see that?                                 |
| 09:56 | 20 | A. Yes.  |
|       | 21 | Q. So there are differences between the two      |
|       | 22 | embodiments. Correct?                            |
|       | 23 | A. There are many other embodiments where I      |
|       | 24 | don't think those differences show up.           |
| 09:56 | 25 | But in Paragraph 13, what you said is            |
|       |    | ,  |

| 09:56 | 1  | correct.                                      |
|-------|----|---|
|       | 2  | Q. And you cite to Paragraph 13. Right?       |
|       | 3  | A. I cite many others as well.                |
|       | 4  | Q. Okay. So let's go to Paragraph 27.         |
| 09:56 | 5  | That's another one that you cite to. Correct? |
|       | 6  | A. From Page 41 of the declaration? I don't   |
|       | 7  | see 27 mentioned there.                       |
|       | 8  | Q. All right. Paragraph                       |
|       | 9  | So if you flip to Page 63 of your             |
| 09:57 | 10 | declaration, Paragraph 122. You say:          |
|       | 11 | The recess in Saxler's cap                    |
|       | 12 | layer 24 is optional.                         |
|       | 13 | And you cite to Paragraph 27.                 |
|       | 14 | A. Okay.                                      |
| 09:58 | 15 | Q. Yeah. So if we go back to Saxler at        |
|       | 16 | Paragraph 27.                                 |
|       | 17 | Here again, it says:                          |
|       | 18 | And the transistor may                        |
|       | 19 | further include a gate contact                |
| 09:58 | 20 | recessed into the aluminum                    |
|       | 21 | nitride cap layer                             |
|       | 22 | I'm on one, two, three, four, five            |
|       | 23 | six from the top.                             |
|       | 24 | A. Yes.                                       |
| 09:58 | 25 | Q. (Continued reading:)                       |
|       |    |   |

|       | i  |  |
|-------|----|--|
| 09:58 | 1  | In such embodiments, the                     |
|       | 2  | aluminum layer has a thickness               |
|       | 3  | of from about 5 to about                     |
|       | 4  | 5000 angstroms.                              |
| 09:58 | 5  | Do you see that?                             |
|       | 6  | A. Yes.                                      |
|       | 7  | Q. Okay. And one, two, three, four,          |
|       | 8  | five six from the bottom:                    |
|       | 9  | The transistor may also                      |
| 09:59 | 10 | include a gate contact on the                |
|       | 11 | aluminum nitride cap layer and               |
|       | 12 | not recessed into the aluminum               |
|       | 13 | nitride cap layer. In such                   |
|       | 14 | embodiments, the aluminum                    |
| 09:59 | 15 | nitride cap layer has the                    |
|       | 16 | thickness of about or from                   |
|       | 17 | about 2 angstroms to about                   |
|       | 18 | 20-angstroms.                                |
|       | 19 | Do you see that?                             |
| 09:59 | 20 | A. Yes.                                      |
|       | 21 | Q. Okay. So there are, again, differences in |
|       | 22 | the thickness of the cap layer. Correct?     |
|       | 23 | A. In the embodiments described in           |
|       | 24 | Paragraph 27, yes.                           |
| 09:59 | 25 | Q. Okay. And so, there are differences       |
|       | J  |  |

| 09:59 | 1  | between the recessed and nonrecessed embodiments. |
|-------|----|---|
|       | 2  | Correct?  |
|       | 3  | MS. SPECHT: Objection; form.                      |
|       | 4  | A. I wouldn't agree with that.                    |
| 09:59 | 5  | If you go to Paragraph 52, we could I             |
|       | 6  | could explain that a little better.               |
|       | 7  | Q. Okay. Let's go to 52.                          |
|       | 8  | (Pause.)  |
|       | 9  | Q. I'm there.                                     |
| 10:00 | 10 | A. Okay. 52 in Paragraph 52, they're              |
|       | 11 | referring to Figures 1A through 6. And they       |
|       | 12 | (Reading:)  |
|       | 13 | Thus, while embodiments of                        |
|       | 14 | the present invention are                         |
| 10:00 | 15 | described herein with reference                   |
|       | 16 | to a recessed gate structure or                   |
|       | 17 | a nonrecessed gate structure,                     |
|       | 18 | other embodiments of the                          |
|       | 19 | present invention may include                     |
| 10:00 | 20 | or not include a gate recess.                     |
|       | 21 | So I interpret that to apply to Figure 1A.        |
|       | 22 | Q. Okay. Despite the differences between the      |
|       | 23 | recessed and nonrecessed embodiments that are     |
|       | 24 | specifically recited in Saxler?                   |
| 10:00 | 25 | A. Yes. Because a p-doping can be doped           |
|       |    |   |

|       | i  |  |
|-------|----|--|
| 10:00 | 1  | throughout, and it can be on the surface.        |
|       | 2  | You know, I think you can they                   |
|       | 3  | basically say you can                            |
|       | 4  | It further says:                                 |
| 10:01 | 5  | Embodiments of the present                       |
|       | 6  | invention not be should not                      |
|       | 7  | be construed as limited to the                   |
|       | 8  | particular exemplary                             |
|       | 9  | embodiments.                                     |
| 10:01 | 10 | So I read that to mean it could be doped         |
|       | 11 | throughout if you want to.                       |
|       | 12 | Q. Okay. But the Saxler paragraphs that we       |
|       | 13 | went through describe differences between the    |
|       | 14 | recessed and nonrecessed embodiments in terms of |
| 10:01 | 15 | thicknesses and in terms of dope in regions.     |
|       | 16 | Correct?   |
|       | 17 | MS. SPECHT: Objection; form.                     |
|       | 18 | A. It was pretty clear what was stated in        |
|       | 19 | those paragraphs. So                             |
| 10:02 | 20 | Q. Okay. But it's your opinion that 52           |
|       | 21 | allows for the allows for what, exactly?         |
|       | 22 | A. Well, allows for just what it says:           |
|       | 23 | The embodiments of the                           |
|       | 24 | present invention should not be                  |
| 10:02 | 25 | as construed as limiting to                      |
|       |    |  |

| 10:02 | 1  | the particular exemplary                            |
|-------|----|---|
|       | 2  | embodiment.   |
|       | 3  | So I think you can take all the                     |
|       | 4  | embodiments, and mix and match. That's kind of what |
| 10:02 | 5  | that means to me.                                   |
|       | 6  | Q. So it's your opinion that Saxler provides        |
|       | 7  | support for any gallium nitride transistor?         |
|       | 8  | MS. SPECHT: Objection;                              |
|       | 9  | mischaracterization.                                |
| 10:02 | 10 | Q. Based on Paragraph 52?                           |
|       | 11 | A. No.  |
|       | 12 | Q. Okay. So what are the parameters that are        |
|       | 13 | limited in Paragraph 52?                            |
|       | 14 | A. What they describe in this patent.               |
| 10:02 | 15 | So, Figures 1A through 6, I read that as            |
|       | 16 | it's fair game to pull the recess out of any of     |
|       | 17 | those figures. And they give a variety of           |
|       | 18 | discussion of dopants, different types of dopants,  |
|       | 19 | different distributions.                            |
| 10:03 | 20 | So I think all those embodiments could be           |
|       | 21 | brought into 1A, modified.                          |
|       | 22 | Q. That also talks about different                  |
|       | 23 | thicknesses in the recessed and nonrecessed. Right? |
|       | 24 | A. It in those paragraphs, it did say the           |
| 10:03 | 25 | cap layer was a different thickness.                |

| 10:03 | 1  | Q. So in your opinion, you can mix and match       |
|-------|----|--|
|       | 2  | all of that?                                       |
|       | 3  | MS. SPECHT: Objection;                             |
|       | 4  | mischaracterizes prior testimony.                  |
| 10:03 | 5  | A. It means that you can within you can            |
|       | 6  | take what's in the embodiments and mix and match.  |
|       | 7  | That's what I mean, because because of the         |
|       | 8  | language that appears in 52.                       |
|       | 9  | They're not these none of these                    |
| 10:04 | 10 | embodiments are limiting.                          |
|       | 11 | Q. Okay. So in your opinion, does Saxler,          |
|       | 12 | based on Paragraph 52, allow for multiple recesses |
|       | 13 | in the cap layer?                                  |
|       | 14 | A. That's not in Saxler. I don't really have       |
| 10:04 | 15 | an opinion on that. I haven't                      |
|       | 16 | So I'm not sure where you know, what               |
|       | 17 | you're getting at, but I don't have an opinion on  |
|       | 18 | it.  |
|       | 19 | Q. You don't have an opinion on that?              |
| 10:04 | 20 | A. Multiple recesses? No.                          |
|       | 21 | Q. Okay. Could it have vertical sidewalls?         |
|       | 22 | A. Could what have vertical sidewalls?             |
|       | 23 | Could a recess? Or                                 |
|       | 24 | Q. Could the recess have vertical sidewalls,       |
| 10:04 | 25 | yes.   |

| 10:04 | 1  | MS. SPECHT: Objection;                             |
|-------|----|--|
|       | 2  | foundation.  |
|       | 3  | A. Not generally, no.                              |
|       | 4  | Q. Does. Does Saxler                               |
| 10:04 | 5  | Let's go back to Paragraph 27.                     |
|       | 6  | There it's talking about the cap layer             |
|       | 7  | thickness. Right?                                  |
|       | 8  | A. Yes.  |
|       | 9  | Q. And there is a wide range from about 5 to       |
| 10:05 | 10 | about 5000 angstroms for the thickness of the cap  |
|       | 11 | layer. Right?                                      |
|       | 12 | A. Correct.  |
|       | 13 | Q. And that's in connection with the recessed      |
|       | 14 | embodiment. Correct?                               |
| 10:05 | 15 | A. Yes.  |
|       | 16 | Q. And then if we go down below, we're             |
|       | 17 | talking about a thickness of 2 to 20 angstroms for |
|       | 18 | the nonrecessed embodiment. Correct?               |
|       | 19 | A. That's what it says.                            |
| 10:06 | 20 | Q. Okay. In your opinion, does Paragraph 52        |
|       | 21 | allow for a nonrecessed cap layer to have          |
|       | 22 | 5000 angstroms thickness?                          |
|       | 23 | MS. SPECHT: Objection; form.                       |
|       | 24 | A. As I said before, I think you could take        |
| 10:06 | 25 | all the embodiments and bring in which ones you    |

| 10:06 | 1  | want, depending on what you're trying to accomplish. |
|-------|----|--|
|       | 2  | Q. So in your opinion, are there any                 |
|       | 3  | transistor are there any gate structures that are    |
|       | 4  | outside the scope of Saxler?                         |
| 10:07 | 5  | A. You mean, in general                              |
|       | 6  | Q. Yes.  |
|       | 7  | A out there in the world?                            |
|       | 8  | Of course, there are.                                |
|       | 9  | Q. Which ones?                                       |
| 10:07 | 10 | A. How about a T gate for a microwave                |
|       | 11 | transistor? That's not described in Saxler.          |
|       | 12 | Q. I'm not talking about application. I'm            |
|       | 13 | talking about the gate structure shape.              |
|       | 14 | A. There are T gates. There are W gates.             |
| 10:07 | 15 | There's V gates used in microwave devices. There     |
|       | 16 | are many types of gate structures.                   |
|       | 17 | Q. So there are certain                              |
|       | 18 | But in your opinion, aren't Saxler just              |
|       | 19 | isn't Saxler just providing some examples?           |
| 10:07 | 20 | A. Of gate structures?                               |
|       | 21 | Q. Yes.  |
|       | 22 | A. Yeah, there's examples of gate structures         |
|       | 23 | in Saxler.   |
|       | 24 | Q. So are you saying that T gate structures          |
| 10:07 | 25 | are not disclosed by Saxler?                         |
|       |    |  |

| 10:08 | 1  | A. Well, Figure 1A has a gate contact that          |
|-------|----|---|
|       | 2  | kind of looks like a T, but those aren't the same   |
|       | 3  | kind of gates used in microwave devices.            |
|       | 4  | So you asked: Are there any other types             |
| 10:08 | 5  | of gates? And there are a lot. And they a lot       |
|       | 6  | of the differences appear in microwave devices,     |
|       | 7  | which these are not, generally.                     |
|       | 8  | Q. Okay. So are there any gate structures           |
|       | 9  | that fall outside the scope of Saxler, in your      |
| 10:08 | 10 | opinion, that would be specific for HEMTs?          |
|       | 11 | A. As I said, there's a lot of other gate           |
|       | 12 | structures used in HEMTs that aren't described in   |
|       | 13 | Saxler.   |
|       | 14 | Q. All right. You mentioned "T gate," but I         |
| 10:08 | 15 | think Saxler talks about T gates. Right?            |
|       | 16 | A. Yeah, he does have a gate that looks like        |
|       | 17 | a T gate, but that's not the way you would do it in |
|       | 18 | a microwave device. So the entire gate structure is |
|       | 19 | different, even though it kind of is 1A kind of     |
| 10:09 | 20 | looks like a T metalization.                        |
|       | 21 | Q. What's different about a microwave gate?         |
|       | 22 | A. You're not going to load a microwave gate        |
|       | 23 | with this cap layer. It will introduce too many     |
|       | 24 | parasitics.   |
| 10:09 | 25 | Q. In your opinion, does Saxler provide             |

| 10:09 | 1  | support for a gate structure having step sidewalls?  |
|-------|----|--|
|       | 2  | MS. SPECHT: Objection;                               |
|       | 3  | foundation.  |
|       | 4  | A. Which could you tell me exactly what              |
| 10:10 | 5  | you mean by a "step sidewall."                       |
|       | 6  | Q. Are you familiar with "step sidewalls"?           |
|       | 7  | A. I think I know what it means. I want to           |
|       | 8  | make sure.   |
|       | 9  | Q. Okay. What's your understanding of that?          |
| 10:10 | 10 | A. Well, it means the sidewall would be              |
|       | 11 | basically looking like maybe a staircase or          |
|       | 12 | something.   |
|       | 13 | Q. Okay. So with that understanding, does            |
|       | 14 | Saxler provide support for a gate structure having   |
| 10:10 | 15 | step sidewalls?                                      |
|       | 16 | A. I don't believe so.                               |
|       | 17 | I could read Saxler and answer that with a           |
|       | 18 | better certainty, but I don't believe it's in there. |
|       | 19 | Q. Does Saxler provide any support for a             |
| 10:11 | 20 | vertical sidewall in its cap layer?                  |
|       | 21 | A. Let's seeif you look at Paragraph 42 of           |
|       | 22 | Saxler.  |
|       | 23 | Q. I'm there.  |
|       | 24 | A. So they're talking about etching these            |
| 10:11 | 25 | walls. And they say typically they have tapered,     |
|       |    |  |

| 1  | rounded, or curved features which is true.   |
|----|--|
| 2  | The etching processes that are used to   |
| 3  | etch that material do not produce the vertical   |
| 4  | sidewalls.   |
| 5  | Q. You discuss vertical sidewalls in your  |
| 6  | declaration. Right?  |
| 7  | A. I believe there's a discussion  |
| 8  | ofdescribing walls.  |
| 9  | Q. Um-hum. And in your opinion   |
| 10 | A. Do you want to point me to where in the   |
| 11 | declaration you're talking about?  |
| 12 | Q. Let me try to find it.  |
| 13 | Paragraph 72, on Page 35.  |
| 14 | A. Okay.   |
| 15 | Q. I'm sorry, 43, 43.  |
| 16 | A. You said "Paragraph 72"?  |
| 17 | Q. "35" wait, I'm sorry.   |
| 18 | You say, "Few structures, if any"  |
| 19 | I'm on one, two, three, four, five   |
| 20 | five from the top, "Few structures"  |
| 21 | Do you see that?   |
| 22 | A. Yes.  |
| 23 | Q. You say:  |
| 24 | Few structures, if any,  |
| 25 | have perfectly vertical  |
|    | 2<br>3<br>4<br>5<br>6<br>7<br>8<br>9<br>10<br>11<br>12<br>13<br>14<br>15<br>16<br>17<br>18<br>19<br>20<br>21<br>22<br>23<br>24 |

| 10:14 | 1  | sidewalls in practice.                          |
|-------|----|---|
|       | 2  | That's your opinion. Right?                     |
|       | 3  | A. It takes extra processing steps to get a     |
|       | 4  | vertical sidewall, and none of those steps are  |
| 10:14 | 5  | described in any of these references. So        |
|       | 6  | So, really, there's no vertical walls in        |
|       | 7  | an actual "cell-G" (phonetic) device.           |
|       | 8  | Q. What extra processing steps would be         |
|       | 9  | required to get vertical sidewalls?             |
| 10:15 | 10 | A. I'd like to make a drawing to illustrate     |
|       | 11 | that. Is that okay?                             |
|       | 12 | It will answer your question.                   |
|       | 13 | Q. Sure.  |
|       | 14 | A. Okay. So I'll make a diagram and try to      |
| 10:15 | 15 | describe it as I make it.                       |
|       | 16 | We start with a semiconductor surface of        |
|       | 17 | gallium nitride or aluminum gallium nitride. We |
|       | 18 | pattern photoresist on it.                      |
|       | 19 | So this is photoresist (indicating).            |
| 10:16 | 20 | So, so far, we just have a planar gallium       |
|       | 21 | nitride surface with photoresist on it. Okay?   |
|       | 22 | And then what we do is: We subject this         |
|       | 23 | sample to a plasma etch.                        |
|       | 24 | Now, the reason it's a plasma etch is           |
| 10:16 | 25 | because this is c-plane gallium phase gallium   |

| 10:16 | 1  | nitride. That's what's that top surface on these     |
|-------|----|--|
|       | 2  | structures, except for the structure in Beach.       |
|       | 3  | The c-plane is impervious to wet chemical            |
|       | 4  | etching. So there are no known wet chemical etches   |
| 10:16 | 5  | to etch that. So we use a plasma etch to etch it.    |
|       | 6  | And the plasma edge has, depending on the            |
|       | 7  | type of plasma etch but the two most common,         |
|       | 8  | there's very little undercut that occurs under the   |
|       | 9  | mask. And so, I'll schematically illustrate what     |
| 10:17 | 10 | these walls generally look like.                     |
|       | 11 | So the first part of the figure I'll call            |
|       | 12 | "A." And then what we do is: We subject this to a    |
|       | 13 | plasma etch, and that arrives on the diagram labeled |
|       | 14 | "B."   |
| 10:17 | 15 | Do you see the rounded that's supposed               |
|       | 16 | to be symmetric, but                                 |
|       | 17 | So you see the rounded shapes that occur.            |
|       | 18 | And then what you have to do, if you want            |
|       | 19 | vertical walls you have to subject this sample to    |
| 10:17 | 20 | what's called a "crystallographic etch."             |
|       | 21 | The only known crystallographic etches are           |
|       | 22 | wet etches.  |
|       | 23 | So the next step is: We subject this to              |
|       | 24 | our crystallographic etch. And what that does is     |
| 10:18 | 25 | what the term "crystallographic etch" means is that  |

| 10:18        | 1  | there is a very strong dependence of etch rate on   |
|--------------|----|---|
|              | 2  | crystal orientation or different crystal planes.    |
|              | 3  | Okay?   |
|              | 4  | And so, the slowest etch planes are the             |
| 10:18        | 5  | ones that will expose themselves.                   |
| 10.10        | 6  | So if you do this correctly the                     |
|              | 7  |   |
|              |    | crystallographic etch, by the way, would be         |
|              | 8  | common examples is KOH solutions or TMAH solutions. |
|              | 9  | These are well-known solutions to achieve this. And |
| 10:18        | 10 | so, now we have the same photoresist.               |
|              | 11 | The side surfaces are non-c-plane                   |
|              | 12 | surfaces. Those will etch in a chemical etch. The   |
|              | 13 | top surface will not.                               |
|              | 14 | So we're going to undercut the mask a               |
| 10:19        | 15 | little bit. And when you do this process, you will  |
|              | 16 | end up with something that looks like this          |
|              | 17 | (indicating).                                       |
|              | 18 | And this wall is because it's a                     |
|              | 19 | crystalline plane, is 90 degrees.                   |
| 10:19        | 20 | And there's still a sloped portion below            |
|              | 21 | that that evolves when you do this.                 |
|              | 22 | But that's what happens.                            |
|              | 23 | That's how you create a vertical wall in            |
|              | 24 | gallium nitride, c-plane gallium nitride.           |
| 10:19        | 25 | MR. DOSHI: Okay. So let's mark                      |
| <del>-</del> |    |   |

| 10:19 | 1  | this as  |
|-------|----|--|
|       | 2  | A. That's Diagram C after the etch.              |
|       | 3  | And you will notice there's still some           |
|       | 4  | sloped portions down at the bottom.              |
| 10:20 | 5  | When you get near the bottom, it exposes a       |
|       | 6  | plane here. And that's what gives these slopes a |
|       | 7  | slower edge plane.                               |
|       | 8  | MR. DOSHI: Okay. Let's mark                      |
|       | 9  | this as 2002.                                    |
| 10:20 | 10 | We'll put it in 1382.                            |
|       | 11 | (Whereupon, Exhibit 2002 was marked for          |
|       | 12 | identification.)                                 |
|       | 13 | MR. DOSHI: Thank you.                            |
|       | 14 | BY MR. DOSHI:                                    |
| 10:20 | 15 | Q. And so, this is A, B, and C panels. And       |
|       | 16 | the C panel is in red, which is after the        |
|       | 17 | crystallographic etch.                           |
|       | 18 | Is that correct?                                 |
|       | 19 | A. Yes. It recesses in because it undercuts      |
| 10:20 | 20 | the resist a little bit.                         |
|       | 21 | It doesn't recess much, but it exposes           |
|       | 22 | that slow etch plane.                            |
|       | 23 | All the other planes will be removed             |
|       | 24 | because they etch quickly.                       |
| 10:21 | 25 | Q. Okay. You earlier testified that there        |
|       |    |  |

| 10:21 | 1  | are no additional processes that are disclosed by  |
|-------|----|--|
|       | 2  | Saxler.  |
|       | 3  | A. None of the references disclose what I put      |
|       | 4  | in that diagram.                                   |
| 10:21 | 5  | And you'll notice there's additional               |
|       | 6  | vertical penetration when you do that              |
|       | 7  | crystallographic etch. And that could be quite     |
|       | 8  | problematic for a HEMT device, because there's so  |
|       | 9  | much going on near the surface.                    |
| 10:21 | 10 | So it's not surprising that they don't use         |
|       | 11 | this step.   |
|       | 12 | Q. So since they don't use that step, in your      |
|       | 13 | opinion they cannot achieve these 90-degree        |
|       | 14 | sidewalls.   |
| 10:21 | 15 | Is that correct?                                   |
|       | 16 | A. That is the only way it is known to be          |
|       | 17 | done.  |
|       | 18 | Q. Okay. So let me ask again.                      |
|       | 19 | So since Saxler doesn't use the steps that         |
| 10:22 | 20 | you've described here in Exhibit 2002, Saxler does |
|       | 21 | not or cannot achieve a 90-degree sidewall.        |
|       | 22 | Correct?   |
|       | 23 | A. That's correct or Yoshida, for that             |
|       | 24 | matter.  |
| 10:22 | 25 | COURT REPORTER: Excuse me.                         |

| 10:22 | 1  | What was that term, "Yoshida"?                    |
|-------|----|---|
|       | 2  | THE WITNESS: It's the author of                   |
|       | 3  | another primary reference of prior art.           |
|       | 4  | COURT REPORTER: Would you spell                   |
| 10:22 | 5  | that for me.                                      |
|       | 6  | THE WITNESS: Y-o-s-h-i-d-a.                       |
|       | 7  | COURT REPORTER: Thank you.                        |
|       | 8  | BY MR. DOSHI:                                     |
|       | 9  | Q. So this discussion started with                |
| 10:23 | 10 | Paragraph 52. And I believe my question that      |
|       | 11 | started this was whether Saxler candiscloses      |
|       | 12 | or provides support for vertical sidewalls of the |
|       | 13 | cap layer.  |
|       | 14 | And we went down this path. And your              |
| 10:24 | 15 | conclusion is that it does not.                   |
|       | 16 | Is that correct?                                  |
|       | 17 | A. That's what one skilled in the art would       |
|       | 18 | know: Without a crystallographic edge, it doesn't |
|       | 19 | exist.  |
| 10:24 | 20 | Q. Okay. Let's talk about how we get to the       |
|       | 21 | figure that you put together or you asked         |
|       | 22 | somebody to put together for you                  |
|       | 23 | A. Okay.  |
|       | 24 | Q on Page 41 of your declaration for              |
| 10:24 | 25 | '347.   |
|       |    | ·   |

| 10:24 | 1  | Would the precursor to that have a gate              |
|-------|----|--|
|       | 2  | contact on top?                                      |
|       | 3  | MS. SPECHT: Objection;                               |
|       | 4  | foundation.  |
| 10:24 | 5  | Q. Okay.   |
|       | 6  | A. I don't know what you mean by "precursor"?        |
|       | 7  | Q. Okay. So if we were to make the structure         |
|       | 8  | that is depicted on Page 41, it would start with the |
|       | 9  | substrate. Correct?                                  |
| 10:25 | 10 | A. Yes.  |
|       | 11 | Q. And a channel layer on top of that?               |
|       | 12 | A. Yes.  |
|       | 13 | Q. And a barrier layer on top of that?               |
|       | 14 | A. Yes.  |
| 10:25 | 15 | Q. And then a cap layer, probably, extending         |
|       | 16 | all the way through, right, across the top of the    |
|       | 17 | structure, over the barrier layer?                   |
|       | 18 | A. It doesn't contact it doesn't come in             |
|       | 19 | contact with the Ohmic contacts. But                 |
| 10:25 | 20 | Q. Not yet.  |
|       | 21 | A. Huh?  |
|       | 22 | Q. Not yet.  |
|       | 23 | I'm trying to go through the fabrication             |
|       | 24 | process for this.                                    |
| 10:25 | 25 | A. Oh, okay.   |

| 10:25 | 1  | Q. Does that make sense to you?                      |
|-------|----|--|
|       | 2  | A. The fabrication process?                          |
|       | 3  | Q. Yes.  |
|       | 4  | A. Sure, yeah.                                       |
| 10:25 | 5  | Q. So then what you have in green on Page 41         |
|       | 6  | would likely go across. Correct?                     |
|       | 7  | A. Yes. That layer has to be removed to              |
|       | 8  | place the Ohmic contacts.                            |
|       | 9  | Q. Okay. So once the contacts are in, would          |
| 10:25 | 10 | it look a lot like Figure 1B of Saxler?              |
|       | 11 | A. No.   |
|       | 12 | Q. No?   |
|       | 13 | A. No. 1B is a strange cartoon. It's not             |
|       | 14 | let me make sure I'm talking about the right figure. |
| 10:26 | 15 | It's an idealized cartoon.                           |
|       | 16 | I've never seen a device built that way,             |
|       | 17 | where the sides of the Ohmics are able to butt up    |
|       | 18 | against the cap layer you're not going to be able    |
|       | 19 | to fabricate that.                                   |
| 10:26 | 20 | You could fabricate something that is                |
|       | 21 | intended to you know, this can be like a, I don't    |
|       | 22 | know, some sort of a crude design.                   |
|       | 23 | But there's no way to place Ohmic contacts           |
|       | 24 | and butt them up against that cap layer with no gap  |
| 10:26 | 25 | in between, as shown.                                |

| 10:26 | 1  | There's no standard process to do that.              |
|-------|----|--|
|       | 2  | Q. Okay. And then once the Ohmic contacts            |
|       | 3  | are in, then the gate contact how is that formed     |
|       | 4  | on top of the cap layer?                             |
| 10:27 | 5  | A. That can be formed multiple ways, but             |
|       | 6  | the  |
|       | 7  | Probably the most straightforward is: You            |
|       | 8  | pattern that you do this before you place the        |
|       | 9  | Ohmics. You can put the Ohmics after and they        |
| 10:27 | 10 | can go in either order. But to me, it looks          |
|       | 11 | straightforward to                                   |
|       | 12 | The green goes all the way across. Then              |
|       | 13 | you etch the you plasma etch the green layer.        |
|       | 14 | And then you one way to do it.                       |
| 10:27 | 15 | And remember, there's always multiple ways           |
|       | 16 | of building these things.                            |
|       | 17 | So then youyou, with some technique,                 |
|       | 18 | evaporate or sputter metal on the surface. And you   |
|       | 19 | put resist on that and etch the metal away.          |
| 10:28 | 20 | And in other embodiments where we bring in           |
|       | 21 | other references, we'll use a self-aligned structure |
|       | 22 | to place that gate.                                  |
|       | 23 | But it can be done multiple ways.                    |
|       | 24 | Q. And so, that would involve masking and            |
| 10:28 | 25 | etching steps, I think you said. Right?              |

| 10:28 | 1  | A. Yeah. You have to mask the gate.              |
|-------|----|--|
|       | 2  | But you can etch the green and the gate          |
|       | 3  | metal using the same mask. That would be what we |
|       | 4  | would refer to as a "self-aligned" process.      |
| 10:29 | 5  | Q. And where is that? in Saxler?                 |
|       | 6  | A. No. We bring in the self-aligned with         |
|       | 7  | other references: Beach and Ahn.                 |
|       | 8  | Wait Ahn's only in one of these cases.           |
|       | 9  | I don't want to get confused.                    |
| 10:29 | 10 | Where is that grounds that thing right           |
|       | 11 | there.   |
|       | 12 | Q. I'll represent Ahn is in '347. So             |
|       | 13 | And that's what we're talking about right        |
|       | 14 | now.   |
| 10:29 | 15 | A. All right. I'm just going to                  |
|       | 16 | double-check.                                    |
|       | 17 | Q. Yeah.   |
|       | 18 | (Witness reading.)                               |
|       | 19 | A. And, yes, Ahn you're correct.                 |
| 10:29 | 20 | So Ahn's in this case.                           |
|       | 21 | Q. Okay. So Saxler does not talk about           |
|       | 22 | self-alignment?                                  |
|       | 23 | A. It may be in there, but I don't I don't       |
|       | 24 | recall it's in there. I don't think it is.       |
| 10:30 | 25 | Saxler has other references that like            |

| 10:30 | 1  | Sheppard, Smith that give a lot of details on        |
|-------|----|--|
|       | 2  | fabrication, if you're interested.                   |
|       | 3  | Q. And you discussed those in your                   |
|       | 4  | declaration. Correct?                                |
| 10:30 | 5  | A. Correct.  |
|       | 6  | Q. Figure 1A has a cap layer that is higher          |
|       | 7  | than the Ohmic contact. And in 1B, it shows that     |
|       | 8  | it's about the same height.                          |
|       | 9  | Do you see that?                                     |
| 10:31 | 10 | A. Yes.  |
|       | 11 | Q. That's different thicknesses of the cap           |
|       | 12 | layer?   |
|       | 13 | (No response.)                                       |
|       | 14 | Q. Does that represent different thicknesses         |
| 10:31 | 15 | of the cap layer? Sorry.                             |
|       | 16 | A. To be honest with you, I don't know what          |
|       | 17 | 1B represents because it's not something you can     |
|       | 18 | fab.   |
|       | 19 | What it clearly shows is: There's no                 |
| 10:31 | 20 | recess.  |
|       | 21 | Q. And what about Figure 1A; do you think            |
|       | 22 | that's a fair representation of what Saxler's trying |
|       | 23 | to achieve?  |
|       | 24 | A. Yes. You'll note that the vertical scale          |
| 10:32 | 25 | of these diagrams is exaggerated, so you could see   |

| 1  | details of the epitaxial layer.  |
|----|--|
| 2  | But aside from that, yes.  |
| 3  | Q. Do you expect the gate contact of   |
| 4  | Figure~1A to be centered, as depicted?   |
| 5  | A. There are without self-alignment, it's  |
| 6  | certainly possible to use lithographic techniques to   |
| 7  | place that in the center, yes.   |
| 8  | Q. But for 1B, it's not possible to be   |
| 9  | abutting the cap layer abutting on the contact.  |
| 10 | Right?   |
| 11 | A. Yeah. I just don't know how you build   |
| 12 | something like that.   |
| 13 | MR. DOSHI: All right. Good   |
| 14 | time for a break?  |
| 15 | THE WITNESS: Okay.   |
| 16 | MR. DOSHI: Off the record.   |
| 17 | (Whereupon, a recess was taken   |
| 18 | from 10:33 a.m. until 10:47 a.m.)  |
| 19 | BY MR. DOSHI:  |
| 20 | Q. We are still talking about Saxler. I want   |
| 21 | to take you to Figure 1A.  |
| 22 | Are you there?   |
| 23 | A. Figure 1A?  |
| 24 | Q. Yeah.   |
| 25 | A. Yeah. We were on Page 41, I guess?  |
|    | 2<br>3<br>4<br>5<br>6<br>7<br>8<br>9<br>10<br>11<br>12<br>13<br>14<br>15<br>16<br>17<br>18<br>19<br>20<br>21<br>22<br>23<br>24 |

| 10:47 | 1  | Q. Well, I'm going to take you to Saxler,         |
|-------|----|---|
|       | 2  | actually.   |
|       | 3  | A. Oh, okay.                                      |
|       | 4  | Q. Figure 1A.                                     |
| 10:47 | 5  | A. All right.                                     |
|       | 6  | (Pause.)  |
|       | 7  | A. Okay.  |
|       | 8  | Q. Okay. And in your opinion, is that an          |
|       | 9  | enhancement mode transistor?                      |
| 10:48 | 10 | A. Figure 1A?                                     |
|       | 11 | Q. Yeah let's back up.                            |
|       | 12 | You opine on enhancement mode and                 |
|       | 13 | depletion. Right?                                 |
|       | 14 | A. Yes.   |
| 10:48 | 15 | Q. Okay. And you know what "enhancement           |
|       | 16 | mode" means. Correct?                             |
|       | 17 | A. Yes, I do.                                     |
|       | 18 | Q. What is an enhancement mode transistor?        |
|       | 19 | generally speaking.                               |
| 10:48 | 20 | A. Generally speaking, when there's 0 volts       |
|       | 21 | applied to the gate, it                           |
|       | 22 | The device is in an off state, and you            |
|       | 23 | have to apply a positive bias to the gate to turn |
|       | 24 | the device on.                                    |
| 10:49 | 25 | And that's generally what people would            |
|       |    |   |

| 10:49 | 1  | call "enhancement mode" although, it has other      |
|-------|----|---|
|       | 2  | meanings as well.                                   |
|       | 3  | But in the context of this, I think that's          |
|       | 4  | a good representation.                              |
| 10:49 | 5  | Q. Okay. In your opinion, is Figure 1A an           |
|       | 6  | enhancement mode transistor?                        |
|       | 7  | A. As it's drawn, it would be a depletion           |
|       | 8  | mode device unless the gate contact penetrated deep |
|       | 9  | into the barrier layer, which that's not the way    |
| 10:49 | 10 | it's shown.   |
|       | 11 | Q. And I think you state that in                    |
|       | 12 | Paragraph 146 of your declaration, which I believe  |
|       | 13 | is on Page it is on Page 75.                        |
|       | 14 | A. Yes. On the fourth line from the bottom,         |
| 10:50 | 15 | yeah.   |
|       | 16 | Q. Great. And then if we turn back to               |
|       | 17 | Saxler, Figure 1B.                                  |
|       | 18 | Now, before the break, we were talking              |
|       | 19 | about how the cap layer that this is let me         |
| 10:50 | 20 | rephrase.   |
|       | 21 | Before the break, you testified that                |
|       | 22 | Figure 1B may not have a cap layer that abuts the   |
|       | 23 | Ohmic contact.                                      |
|       | 24 | Is that a fair representation?                      |
| 10:50 | 25 | A. I think what I said was: It would not be         |

| 10:50 | 1  | straightforward at all to fabricate such a         |
|-------|----|--|
|       | 2  | structure.   |
|       | 3  | Q. Okay. Is it possible to etch the cap            |
|       | 4  | layer, deposit a metal over the cap layer and into |
| 10:51 | 5  | the vias, if you will, next to the cap layer?      |
|       | 6  | A. Wait a minute. Are we talking 1B? Or            |
|       | 7  | Q. Yeah, I'm talking 1B.                           |
|       | 8  | I'm just I'm trying to understand.                 |
|       | 9  | You said that there aren't any mechanisms          |
| 10:51 | 10 | by which processes by which you can form 1B.       |
|       | 11 | Is that right?                                     |
|       | 12 | A. Yes. It's basically because the Ohmic           |
|       | 13 | contacts button and are perfectly aligned and butt |
|       | 14 | up against the cap layer. That's the way it's      |
| 10:51 | 15 | drawn.   |
|       | 16 | Q. Okay.   |
|       | 17 | A. And they're also the same thickness             |
|       | 18 | which would rarely be the case.                    |
|       | 19 | Q. So if we go to 72, though Paragraph 72          |
| 10:52 | 20 | of Saxler.   |
|       | 21 | A. Oh, Saxler.                                     |
|       | 22 | Q. Yeah.   |
|       | 23 | A. Okay.   |
|       | 24 | Q. At the fourth from the bottom, it says:         |
| 10:52 | 25 | In such a case                                     |

| 10:52 | 1  | Do you see that?                                  |
|-------|----|---|
| 10101 | 2  | A. Yes.   |
|       |    |   |
|       | 3  | Q. It says:                                       |
|       | 4  | A dope region would not                           |
| 10:52 | 5  | extend to the Ohmics contacts,                    |
|       | 6  | which may be isolated from the                    |
|       | 7  | dope region by an insulating                      |
|       | 8  | region such as a silicon                          |
|       | 9  | nitride layer or gap.                             |
| 10:52 | 10 | Do you see that?                                  |
|       | 11 | A. Yes.   |
|       | 12 | Q. Does that imply that there are instances       |
|       | 13 | where the dope region would contact the Ohmic     |
|       | 14 | contacts?   |
| 10:52 | 15 | MS. SPECHT: Objection; form.                      |
|       | 16 | A. I would say no. It will do the device no       |
|       | 17 | good to do that. It'll only potentially introduce |
|       | 18 | some shunt conductance to the 2D gas, a very bad  |
|       | 19 | thing. So I don't think so.                       |
| 10:53 | 20 | You'd have a gap.                                 |
|       | 21 | Q. So 72 says:                                    |
|       | 22 | Further, in certain                               |
|       | 23 | embodiments of the present                        |
|       | 24 | invention   |
| 10:53 | 25 | Right?  |
|       |    |   |

| 10:53 | 1  | And then, it continues that:                         |
|-------|----|--|
|       | 2  | the doped region would                               |
|       | 3  | not extend to the Ohmic                              |
|       | 4  | contacts.  |
| 10:53 | 5  | Are there instances are there                        |
|       | 6  | embodiments contemplated by Saxler where the cap     |
|       | 7  | layer extends from Ohmic contact to Ohmic contact    |
|       | 8  | without the doped layer Dope Region 40?              |
|       | 9  | MS. SPECHT: Objection; form.                         |
| 10:53 | 10 | A. So your question was would you just               |
|       | 11 | repeat the question, please.                         |
|       | 12 | Q. Sure. Does Saxler contemplate a cap layer         |
|       | 13 | that contacts both Ohmic contacts?                   |
|       | 14 | A. That's certainly what's shown in 1B.              |
| 10:54 | 15 | But, remember, Saxler has a lot of                   |
|       | 16 | different structures for cap layers and some of them |
|       | 17 | are insulating.                                      |
|       | 18 | So if the cap layer's insulating, it would           |
|       | 19 | function.  |
| 10:54 | 20 | Q. Okay.   |
|       | 21 | A. If it's conducting, it would be a                 |
|       | 22 | disaster.  |
|       | 23 | Q. Why would it be a disaster?                       |
|       | 24 | A. Because when you apply a gate potential,          |
| 10:54 | 25 | you're trying to modify the two-dimensional electron |

| 10:54 | 1  | gas. And you want all of the conduction, all the    |
|-------|----|---|
|       | 2  | drain current in the device, to come from the       |
|       | 3  | two-dimensional electron gas, because that's what's |
|       | 4  | gated.  |
| 10:54 | 5  | If you have a conducting cap layer in 1B,           |
|       | 6  | there would always be current flowing from source   |
|       | 7  | to or electron flow or current from drain to        |
|       | 8  | source that would be going through the cap layer    |
|       | 9  | that wouldn't be affected, necessarily, by the gate |
| 10:55 | 10 | bias.   |
|       | 11 | So you never want a parallel conduction             |
|       | 12 | path to the two-dimensional electron gas.           |
|       | 13 | Q. And so, going back to 1B, is that in             |
|       | 14 | your well, is Figure 1B an enhancement mode         |
| 10:56 | 15 | transistor?   |
|       | 16 | A. If the cap layer were p-doped at the             |
|       | 17 | correct amount and the thickness was correct, it    |
|       | 18 | could be an enhancement mode device.                |
|       | 19 | Q. When you say "thickness is" I think you          |
| 10:56 | 20 | said "correct" what do you mean by that?            |
|       | 21 | "Thickness," meaning the height or the              |
|       | 22 | width?  |
|       | 23 | A. The height.                                      |
|       | 24 | Q. Okay. Does Saxler say "enhancement mode"?        |
| 10:57 | 25 | I think you said it does not. Right?                |

|       | I  |  |
|-------|----|--|
| 10:57 | 1  | COURT REPORTER: Did you say                      |
|       | 2  | what?  |
|       | 3  | MR. DOSHI: Sorry.                                |
|       | 4  | COURT REPORTER: I'm sorry.                       |
| 10:57 | 5  | Q. Does Saxler say that does Saxler use          |
|       | 6  | the term "enhancement mode"?                     |
|       | 7  | A. My recollection is it doesn't, but I'll be    |
|       | 8  | happy to look for it.                            |
|       | 9  | Q. No. I think Paragraph 99 on Page 53 of        |
| 10:57 | 10 | your declaration, I believe you say well, you do |
|       | 11 | say:   |
|       | 12 | Although Saxler does not                         |
|       | 13 | use the phrase "enhancement                      |
|       | 14 | mode," this transistor indeed                    |
| 10:57 | 15 | constitutes a normally off                       |
|       | 16 | enhancement mode gallium                         |
|       | 17 | nitride transistor when these                    |
|       | 18 | p-type dopants are placed in                     |
|       | 19 | the cap layer.                                   |
| 10:57 | 20 | Do you see that?                                 |
|       | 21 | A. You're on Page 53?                            |
|       | 22 | Q. Yes; Paragraph 99.                            |
|       | 23 | A. Okay. Well, that's                            |
|       | 24 | If you remove the recess and add p-doping        |
| 10:58 | 25 | to the cap layer, you can turn you can easily    |
|       |    |  |

| 10:58 | 1  | turn Saxler's device into an enhancement mode        |
|-------|----|--|
|       | 2  | device.  |
|       | 3  | That p-cap layer is what that's the                  |
|       | 4  | primary difference between a depletion and           |
| 10:58 | 5  | enhancement mode device.                             |
|       | 6  | So they're very compatible with each other           |
|       | 7  | because they only differ by, you know, that one      |
|       | 8  | feature to go from a depletion mode to an            |
|       | 9  | enhancement mode.                                    |
| 10:58 | 10 | So, you know, one skilled in the art would           |
|       | 11 | be familiar with both.                               |
|       | 12 | Q. In your opinion, would that be would              |
|       | 13 | Figure 1B be a reasonably well working enhancement   |
|       | 14 | mode transistor?                                     |
| 10:59 | 15 | A. I think you'd want to separate the Ohmics         |
|       | 16 | from the cap layer, because that structure, as       |
|       | 17 | shown, would have these shunt problems I was talking |
|       | 18 | about, potentially.                                  |
|       | 19 | Q. And the 2DEG where is the 2DEG depleted           |
| 10:59 | 20 | in Figure 1B?  |
|       | 21 | A. I think it'd be useful to make another            |
|       | 22 | drawing.   |
|       | 23 | Q. Okay.   |
|       | 24 | A. I think if I if I do the drawing for              |
| 11:00 | 25 | 1A, it will encompass everything in both figures.    |

|       | •  |   |
|-------|----|---|
| 11:00 | 1  | Q. I'm specifically asking about 1B, because      |
|       | 2  | you said that it could be in enhancement mode.    |
|       | 3  | I'm trying to understand                          |
|       | 4  | A. Well, so can 1A if you remove the recess       |
| 11:00 | 5  | and p-dope the cap.                               |
|       | 6  | So  |
|       | 7  | Q. Right.   |
|       | 8  | A what I was going to do is do it for the         |
|       | 9  | modified structure, because                       |
| 11:00 | 10 | Q. No yeah, but I'm more interested in 1B,        |
|       | 11 | because I understand your position in             |
|       | 12 | Paragraph 146                                     |
|       | 13 | A. Okay.  |
|       | 14 | Q regarding 1A.                                   |
| 11:00 | 15 | But I'm talking about 1B and how that             |
|       | 16 | would function as an enhancement mode transistor. |
|       | 17 | A. Okay. All I'm doing in Diagram A is            |
|       | 18 | trying to reproduce Figure 1B.                    |
|       | 19 | Okay. So I'm going to indicate the                |
| 11:01 | 20 | boundaries between the Ohmics and I forgot to put |
|       | 21 | the gate on.                                      |
|       | 22 | And so, you could now think about                 |
|       | 23 | producing a profile of the electron gas, which is |
|       | 24 | getting at the heart of your question, across a   |
| 11:02 | 25 | device from source to drain.                      |

| 11:02 | 1  | So I'll call this the "source" over here,            |
|-------|----|--|
|       | 2  | and "gate," and the "drain."                         |
|       | 3  | Okay. So the 2D gas is, more or less, the            |
|       | 4  | same under the Ohmic contact. So you have a 2D gas   |
| 11:02 | 5  | here and here (indicating).                          |
|       | 6  | So no matter what biases you apply, you're           |
|       | 7  | always going to have a 2D gas in those regions.      |
|       | 8  | Q. So just for the record, "2DEG," right, is         |
|       | 9  | what you're referring to?                            |
| 11:02 | 10 | A. 2-Dimensional Electron Gas "2DEG."                |
|       | 11 | I don't like that term, but that's all               |
|       | 12 | right.   |
|       | 13 | And then so this is when the device is               |
|       | 14 | in the off state. Okay?                              |
| 11:03 | 15 | And so, the negative charge associated               |
|       | 16 | with that p-type layer, that comes from the acceptor |
|       | 17 | impurities you dope it with.                         |
|       | 18 | That negative charge and so, we're not               |
|       | 19 | applying any gate bias that negative charge is       |
| 11:03 | 20 | sufficient in density to deplete all of the 2D       |
|       | 21 | the "2DEG," if you like out of the channel.          |
|       | 22 | So theit would look something like this              |
|       | 23 | (indicating).  |
|       | 24 | And so, this is a I'll call it the                   |
| 11:03 | 25 | sheet concentration of the 2D electron gas as a      |

| 11:04 | 1  | function of position.                               |
|-------|----|---|
|       | 2  | This is for it's in the off state and               |
|       | 3  | low drain bias, just because it's easier to draw    |
|       | 4  | that way. Okay?                                     |
| 11:04 | 5  | And then you apply a                                |
|       | 6  | And by the way, it doesn't matter if                |
|       | 7  | there's gaps between the source and the gate. It's  |
|       | 8  | just it's just not something that matters.          |
|       | 9  | So in other words, you can have gaps in             |
| 11:04 | 10 | this channel, and the 2D gas will still be induced  |
|       | 11 | when it's in the on state.                          |
|       | 12 | So now on Diagram C, we'll draw in the on           |
|       | 13 | state. Nothing's changed about the Ohmic contacts   |
|       | 14 | and the 2D gas concentration under them.            |
| 11:05 | 15 | So this is meant to be the same. The 2D             |
|       | 16 | gas hasn't changed under the Ohmics.                |
|       | 17 | Now, if you forward biases to turn this             |
|       | 18 | on, you can actually and you will actually increase |
|       | 19 | the 2D gas concentration it depends on how hard     |
| 11:05 | 20 | you turn it on over what's under the Ohmic          |
|       | 21 | contacts.   |
|       | 22 | So at low drain bias, it would actually             |
|       | 23 | look like this when it's on.                        |
|       | 24 | And that same figure would apply to 1A.             |
| 11:05 | 25 | But you have to modify it because there's sloped    |

| 11:05 | 1  | sidewall shown.                                      |
|-------|----|--|
|       | 2  | So the acceptor densities the sheet                  |
|       | 3  | density, which is a product of the volume density    |
|       | 4  | times the thickness, it changes as you move through. |
| 11:05 | 5  | So there's a more gradual transition in              |
|       | 6  | 1A, but it basically looks the same.                 |
|       | 7  | MR. DOSHI: Okay. Let's mark                          |
|       | 8  | this drawing as Exhibit 2003 for 1382                |
|       | 9  | 2003.  |
| 11:06 | 10 | COURT REPORTER: Should I put                         |
|       | 11 | "1382" on there for you?                             |
|       | 12 | No? Okay.  |
|       | 13 | MS. SPECHT: You can use the                          |
|       | 14 | same exhibit in both proceedings if you              |
| 11:06 | 15 | want. So just leave it.                              |
|       | 16 | (Whereupon, Exhibit 2003 was marked for              |
|       | 17 | identification.)                                     |
|       | 18 | BY MR. DOSHI:  |
|       | 19 | Q. Okay. In your explanation, you said it            |
| 11:06 | 20 | depends on how hard you turn it on.                  |
|       | 21 | What did you mean by that?                           |
|       | 22 | A. Okay. There's something called a                  |
|       | 23 | "threshold voltage." That's the onset of             |
|       | 24 | conduction.  |
| 11:06 | 25 | Q. Um-hum.   |
|       |    |  |

| 11:06 | 1  | A. And as you increase the gate voltage above        |
|-------|----|--|
|       | 2  | the threshold voltage, you're inducing more and more |
|       | 3  | 2D gas under that gate region.                       |
|       | 4  | Q. Okay. And earlier you had indicated that          |
| 11:07 | 5  | the thickness may need to be reduced for 1B and for  |
|       | 6  | the for it to operate as enhancement mode?           |
|       | 7  | A. I can't say anything about that. There's          |
|       | 8  | no dimensions on here.                               |
|       | 9  | But I'm just saying, you have to have the            |
| 11:07 | 10 | right sheet density of negative charge to fully      |
|       | 11 | deplete the 2D gas out of the channel if you want it |
|       | 12 | to be normally off.                                  |
|       | 13 | Q. Okay. And a gate, as depicted in                  |
|       | 14 | Figure~1B, would that require additional voltage for |
| 11:07 | 15 | it to be turned on as an enhancement mode?           |
|       | 16 | A. Well, you'll design the enhancement mode          |
|       | 17 | device by placing the proper amount of negative      |
|       | 18 | charge negative sheet charge is what counts to       |
|       | 19 | deplete the 2D gas.                                  |
| 11:07 | 20 | So thethat will produce a threshold                  |
|       | 21 | greater than zero if it's in enhancement mode.       |
|       | 22 | So the further you drive it beyond                   |
|       | 23 | 0 volts say you drive it at 1 volt in fact, we       |
|       | 24 | could add another feature to that diagram, if you    |
| 11:08 | 25 | want, to illustrate that.                            |

| 11:08 | 1  | Q. Okay. Can we put that in red?                  |
|-------|----|---|
|       | 2  | A. Yeah.  |
|       | 3  | Q. So you're going to take back 2003              |
|       | 4  | I'm just stating this for the                     |
| 11:08 | 5  | A. No, I gotcha.                                  |
|       | 6  | Q for the record.                                 |
|       | 7  | I'm going to hand you back 2003, and              |
|       | 8  | you're going to add red.                          |
|       | 9  | A. Yeah, we'll put it in red.                     |
| 11:08 | 10 | Sosay this is a gate voltage. That's              |
|       | 11 | approximately equal or greater than the threshold |
|       | 12 | voltage.  |
|       | 13 | And then in blue which I seem to have             |
|       | 14 | lost oh, there it is the threshold the gate       |
| 11:09 | 15 | voltage is considerably larger than that. So, I   |
|       | 16 | don't know, say it's approximately the threshold  |
|       | 17 | voltage plus a couple of volts.                   |
|       | 18 | There is a limit to how hard you can drive        |
|       | 19 | the gate. And so, 2 volts would be driving it     |
| 11:09 | 20 | pretty hard if the threshold was near zero.       |
|       | 21 | So it might look something like that.             |
|       | 22 | And by the way, this is both all of               |
|       | 23 | these are for low drain bias, these diagrams.     |
|       | 24 | Q. Okay. Thank you.                               |
| 11:09 | 25 | A. Um-hum.  |

| 11:09 | 1  | Q. Let's go back to Paragraph 72 of the           |
|-------|----|---|
|       | 2  | Saxler reference you have so many paragraphs, you |
|       | 3  | don't know which one to reach for.                |
|       | 4  | And specifically right in the middle of           |
| 11:11 | 5  | the paragraph, it talks about a "JHEMT."          |
|       | 6  | A. Yes.   |
|       | 7  | Q. Are you familiar with "JHEMTs," Junction       |
|       | 8  | HEMTs?  |
|       | 9  | A. Of course.                                     |
| 11:11 | 10 | Q. Okay. Is that in enhancement mode?             |
|       | 11 | A. No.  |
|       | 12 | Q. Okay.  |
|       | 13 | A. That's not to say they can't be.               |
|       | 14 | But the way it's described here, it would         |
| 11:11 | 15 | be in depletion mode and it's a bad idea.         |
|       | 16 | Q. Let's go to Paragraph 63 of Saxler.            |
|       | 17 | Okay. And this Paragraph 63, this acts            |
|       | 18 | as the cap layer. Correct?                        |
|       | 19 | A. Yes.   |
| 11:13 | 20 | Q. And the formation of the cap layer.            |
|       | 21 | Right?  |
|       | 22 | A. The Paragraph 63?                              |
|       | 23 | Q. Yes.   |
|       | 24 | A. Yeah, it's suggesting you use epitaxial        |
| 11:13 | 25 | growth techniques to produce it.                  |

| 11:13 | 1  | Q. And we talked about that earlier.           |
|-------|----|--|
|       | 2  | It's basically putting down that cap layer     |
|       | 3  | in green and you modify it bigger, Saxler.     |
|       | 4  | Right?   |
| 11:13 | 5  | A. Yes. There's no lithographic processing     |
|       | 6  | that occurs yet. So it's a planar film.        |
|       | 7  | Q. So in 64, we're talking about KOH and       |
|       | 8  | etching.                                       |
|       | 9  | And is in 2002 in Exhibit 2002,                |
| 11:14 | 10 | which is the drawing that you made, you I      |
|       | 11 | think oh, you have I think you have before you |
|       | 12 | 2002, the drawing the first drawing that you   |
|       | 13 | made.  |
|       | 14 | Do you have it?                                |
| 11:14 | 15 | A. Where is it?                                |
|       | 16 | I thought I gave it up, but oh, it's           |
|       | 17 | over here.                                     |
|       | 18 | MS. SPECHT: There it is.                       |
|       | 19 | Q. I apologize. Here it is.                    |
| 11:14 | 20 | A. Okay.                                       |
|       | 21 | Q. I see "KOH" in your notations there.        |
|       | 22 | So   |
|       | 23 | A. Yes.  |
|       | 24 | Q is that the same KOH etching materials?      |
| 11:14 | 25 | A. As soon as you add that's KOH with UV       |

| 11:15 | 1  | stimulation of the etch. And that's not how          |
|-------|----|--|
|       | 2  | crystallographic etches are done, usually. So it's   |
|       | 3  | kind of a different animal.                          |
|       | 4  | If they you could have KOH solutions                 |
| 11:15 | 5  | that don't effectively crystallographic etch. If     |
|       | 6  | it's a crystallographic etch, it'll say it.          |
|       | 7  | Q. And do you understand Paragraph 64 to be          |
|       | 8  | etching the cap layer to drop in the Ohmic contacts? |
|       | 9  | A. Well, they said this etch is done to              |
| 11:16 | 10 | expose the underlying barrier layer.                 |
|       | 11 | And that's where the contacts are placed,            |
|       | 12 | either directly on the barrier or, if you look at    |
|       | 13 | Figure 1A, they're actually recessed into the        |
|       | 14 | barrier.   |
| 11:16 | 15 | Generally, you get better Ohmic contacts             |
|       | 16 | if you recess them into the barrier.                 |
|       | 17 | In fact well, I won't go into any more               |
|       | 18 | detail on that.                                      |
|       | 19 | MR. DOSHI: I'm handing you                           |
| 11:18 | 20 | what's been previously marked as                     |
|       | 21 | Exhibit 1006, which is Yoshida.                      |
|       | 22 | (Whereupon, Exhibit 1006, previously                 |
|       | 23 | marked, was presented to the witness.)               |
|       | 24 | BY MR. DOSHI:  |
| 11:18 | 25 | Q. Have you seen this document before?               |

| 11:18 | 1  | A. Yes.   |
|-------|----|---|
|       | 2  | Q. Okay.  |
|       | 3  | A. It's in the binder here.                         |
|       | 4  | Q. Okay. If you want to use your binder             |
| 11:18 | 5  | copy, that's fine, so long as there are no notes on |
|       | 6  | it.   |
|       | 7  | A. Okay.  |
|       | 8  | Q. We've been talking about Saxler                  |
|       | 9  | enhancement mode.                                   |
| 11:18 | 10 | Is Yoshida an enhancement mode transistor?          |
|       | 11 | A. Yes. There's support for that in here.           |
|       | 12 | Q. And Yoshida has a gate structure. Right?         |
|       | 13 | A. Yes.   |
|       | 14 | Q. Yeah. And do you agree that Yoshida              |
| 11:19 | 15 | deposits and etches the gate material first, before |
|       | 16 | the gate contact?                                   |
|       | 17 | MS. SPECHT: Objection; form.                        |
|       | 18 | A. I don't recall. So I'd like to look.             |
|       | 19 | Q. Sure.  |
| 11:19 | 20 | A. It can certainly be done either way,             |
|       | 21 | but   |
|       | 22 | (Witness reading.)                                  |
|       | 23 | A. Okay. I'm ready to answer the question,          |
|       | 24 | but I forgot the exact language. I don't know if    |
| 11:22 | 25 | you could repeat the question.                      |

| 11:22 | 1  | Q. Yoshida has a fairly clear process,            |
|-------|----|---|
|       | 2  | correct? in terms of creating a structure?        |
|       | 3  | MS. SPECHT: Objection; form.                      |
|       | 4  | A. He has several paragraphs describing           |
| 11:22 | 5  | fabrication.                                      |
|       | 6  | And in the conventional art, he describes         |
|       | 7  | one scenario.                                     |
|       | 8  | The source electrode and                          |
|       | 9  | drain electrode are loaded                        |
| 11:23 | 10 | as a further example, a gate                      |
|       | 11 | electrode is loaded via a                         |
|       | 12 | p-type layer.                                     |
|       | 13 | I'm not sure that implies the order of            |
|       | 14 | process for that particular paragraph.            |
| 11:23 | 15 | And then there's paragraph so that was            |
|       | 16 | Paragraph 2. Paragraph 6, it says:                |
|       | 17 | After performing                                  |
|       | 18 | conventional photolithography                     |
|       | 19 | and etching of the n-type AlGaN                   |
| 11:23 | 20 | layer, a gate electrode,                          |
|       | 21 | source, and drain electrode are                   |
|       | 22 | loaded on.  |
|       | 23 | That's certainly                                  |
|       | 24 | And that particular paragraph doesn't             |
| 11:23 | 25 | imply any order of processing. One skilled in the |
|       |    |   |

|       | _  |  |
|-------|----|--|
| 11:23 | 1  | art would read that as you could do it either way. |
|       | 2  | And then there's another if I can find             |
|       | 3  | it discussion of the fabrication, which appears    |
|       | 4  | in Paragraph 23.                                   |
| 11:24 | 5  | In 23 it would seem to suggest source and          |
|       | 6  | drain contacts come in first, I think. It's not    |
|       | 7  | like do you see what it says?                      |
|       | 8  | Lastly, etching away and                           |
|       | 9  | masking the opening of the SiO2                    |
| 11:24 | 10 | film beneath it, the source and                    |
|       | 11 | drain electrodes were masked                       |
|       | 12 | with the SiO2 film.                                |
|       | 13 | And then later, the gate electrodes were           |
|       | 14 | loaded.  |
| 11:25 | 15 | So that suggests the gate came after the           |
|       | 16 | source and drain.                                  |
|       | 17 | Does that answer your question?                    |
|       | 18 | But the other disclosures seem to imply            |
|       | 19 | you could do it in any order.                      |
| 11:25 | 20 | Q. And the others you're talking about             |
|       | 21 | paragraphs 2 and 6. Correct?                       |
|       | 22 | A. Well, 2 is conventional art. So maybe we        |
|       | 23 | shouldn't  |
|       | 24 | But 6 there's one sentence that says               |
| 11:25 | 25 | you do all this stuff. It doesn't tell you it      |
|       |    |  |

|       | Í  |  |
|-------|----|--|
| 11:25 | 1  | seems to suggest any order will work.              |
|       | 2  | Q. Is 6 under the heading of "Conventional         |
|       | 3  | Art"?  |
|       | 4  | A. It may be well, I don't                         |
| 11:25 | 5  | Q. Because I'm looking at Paragraph 8 at the       |
|       | 6  | bottom there. It says:                             |
|       | 7  | Problems the invention                             |
|       | 8  | seeks to solve.                                    |
|       | 9  | A. Okay.   |
| 11:26 | 10 | (Witness reading.)                                 |
|       | 11 | A. Okay. Well, anyway, the Paragraph 23            |
|       | 12 | seems to suggest that the gate came                |
|       | 13 | (Witness reading.)                                 |
|       | 14 | A. Even in 23, it's not clear what the order       |
| 11:26 | 15 | of the process is, because it almost suggests that |
|       | 16 | what they're doing is: They said they've got an    |
|       | 17 | SiO2 film, which is an insulator over the whole    |
|       | 18 | thing. And then they mask it and open up holes in  |
|       | 19 | that film.   |
| 11:26 | 20 | And then the source, drain electrodes were         |
|       | 21 | masked   |
|       | 22 | (Witness reading.)                                 |
|       | 23 | A. Okay. It says:                                  |
|       | 24 | The source, drain                                  |
| 11:27 | 25 | source and source electrode,                       |

| 11:27 | 1  | drain electrode                                      |
|-------|----|--|
|       | 2  | They call that "G." I don't know why. I              |
|       | 3  | think that's a typo.                                 |
|       | 4  | are masked with the                                  |
| 11:27 | 5  | film and gold was deposited                          |
|       | 6  | Somewhere along the line, they got to                |
|       | 7  | expose the Ohmic contacts.                           |
|       | 8  | And so, the entire process isn't here.               |
|       | 9  | So the gate's formed. It seems to suggest            |
| 11:28 | 10 | the Ohmic contacts are covered up with SiO2.         |
|       | 11 | So the Ohmic contacts really aren't                  |
|       | 12 | completed until you expose the metal so that you can |
|       | 13 | operate the device.                                  |
|       | 14 | So that, by itself                                   |
| 11:28 | 15 | You know you get my point?                           |
|       | 16 | The source-drain contact process wasn't              |
|       | 17 | finished until after the gate. It was started        |
|       | 18 | before the gate. So you call that "gate first, gate  |
|       | 19 | last"? How about "first or last"?                    |
| 11:28 | 20 | Q. Okay. Could we go to Paragraph 19.                |
|       | 21 | A. Yeah.   |
|       | 22 | Q. Okay. So Paragraph 19 and actually,               |
|       | 23 | through 21 it talks abouttalks about the             |
|       | 24 | process. Correct?                                    |
| 11:29 | 25 | A. That's all talking about the epitaxial            |

|       | ĺ  |   |
|-------|----|---|
| 11:29 | 1  | part of the process.                              |
|       | 2  | Q. Got it.  |
|       | 3  | And then Paragraph 22, what is it                 |
|       | 4  | referring to there?                               |
| 11:29 | 5  | A. You're dry etching to etch away the p-type     |
|       | 6  | GaN, except where the gate except where the gate  |
|       | 7  | electrode was to be loaded, exposing the n-type.  |
|       | 8  | (Witness reading.)                                |
|       | 9  | A. So   |
| 11:29 | 10 | (Witness reading.)                                |
|       | 11 | A. Okay. They clearly start the Ohmic             |
|       | 12 | process before the gate.                          |
|       | 13 | But the lastly, Paragraph 23, they                |
|       | 14 | don't seem to finish the Ohmic process till after |
| 11:30 | 15 | the gate.   |
|       | 16 | So I guess you could call it either way.          |
|       | 17 | Q. What significance does that last in the        |
|       | 18 | last two sentences I mean, that last sentence     |
|       | 19 | say?  |
| 11:31 | 20 | And I'm in Paragraph 22                           |
|       | 21 | A. Okay.  |
|       | 22 | Q second-to-the-last line.                        |
|       | 23 | And it starts with:                               |
|       | 24 | and metal Al deposited                            |
| 11:31 | 25 | on the exposed n-type                             |

| 11:31 | 1  | A. Wait a minute. Which I thought you      |
|-------|----|--|
|       | 2  | said "22"?                                 |
|       | 3  | Q. "22," yeah second-to-last line.         |
|       | 4  | A. Okay.                                   |
| 11:31 | 5  | Q. And                                     |
|       | 6  | A. Okay. I see it now.                     |
|       | 7  | Q. Is that metal aluminum?                 |
|       | 8  | A. Yes.                                    |
|       | 9  | Q. And so, that's deposited on the exposed |
| 11:31 | 10 | n-type indium gallium nitride layer 4?     |
|       | 11 | A. Yes.                                    |
|       | 12 | So that's the Ohmic metal.                 |
|       | 13 | Q. That's the                              |
|       | 14 | A. It's not a usual Ohmic metal, but on    |
| 11:31 | 15 | n-GaN, it'll work.                         |
|       | 16 | Q. So 4 is aluminum. Okay.                 |
|       | 17 | And then it says, in 23:                   |
|       | 18 | Lastly, after etching away                 |
|       | 19 | the masking and opening the                |
| 11:32 | 20 | silicon dioxide film beneath               |
|       | 21 | it, the source electrode and               |
|       | 22 | drain electrode locations were             |
|       | 23 | masked with silicon dioxide                |
|       | 24 | film.                                      |
| 11:32 | 25 | Do you see that?                           |
|       |    |  |

| 11:32 | 1  | A. Yes.  |
|-------|----|--|
|       | 2  | Q. And then it says:                                 |
|       | 3  | Au   |
|       | 4  | Gold?  |
| 11:32 | 5  | A. Yes.  |
|       | 6  | Q. (Continued reading:)                              |
|       | 7  | was deposited in the                                 |
|       | 8  | opening portions, and gate                           |
|       | 9  | electrodes G were loaded above                       |
| 11:32 | 10 | the p-type GaN layer 5 to                            |
|       | 11 | fabricate the HEMT shown in                          |
|       | 12 | Figure 1.  |
|       | 13 | Do you see that?                                     |
|       | 14 | A. Yes.  |
| 11:32 | 15 | Q. Okay. And, if we turn to                          |
|       | 16 | A. But that's Figure 1 doesn't appear like           |
|       | 17 | what's described in 23, because the SiO2 isn't shown |
|       | 18 | there. And it obviously was removed to get to that   |
|       | 19 | figure.  |
| 11:33 | 20 | So one could conclude that the Ohmic                 |
|       | 21 | contact process wasn't finished until the SiO2 was   |
|       | 22 | removed, which is not shown here.                    |
|       | 23 | I mean, it certainly started before the              |
|       | 24 | gate was deposited.                                  |
| 11:33 | 25 | I'm just pointing that out. That's all.              |
|       |    |  |

| 11:34 | 1  | Q. Okay. Let's go to Paragraph 17. And that         |
|-------|----|---|
|       | 2  | talks a little bit about the gate material.         |
|       | 3  | Do you agree?                                       |
|       | 4  | A. Yes.   |
| 11:34 | 5  | Q. Okay. So here it says:                           |
|       | 6  | The operation of the p-n                            |
|       | 7  | junction immediately under the                      |
|       | 8  | gate electrode G enables                            |
|       | 9  | voltage control                                     |
| 11:34 | 10 | Do you see that?                                    |
|       | 11 | A. Yes.   |
|       | 12 | Q. Okay. And so, that is describing the             |
|       | 13 | operation of Figure 1?                              |
|       | 14 | A. The operation of what?                           |
| 11:34 | 15 | Q. "Figure 1."                                      |
|       | 16 | A. Yes.   |
|       | 17 | Q. Okay. So for Yoshida to be turned on, you        |
|       | 18 | would need to apply a positive voltage to the gate. |
|       | 19 | Is that correct?                                    |
| 11:36 | 20 | A. Yeah.  |
|       | 21 | There's additional support for that in              |
|       | 22 | Paragraph 23.                                       |
|       | 23 | Q. Okay. I'm there.                                 |
|       | 24 | A. They apply a gate voltage of 3 volts, and        |
| 11:36 | 25 | that's the device is turned on, and it exhibits a   |

```
drain saturation voltage -- meaning, it's acting
11:36
        1
        2
            like an enhancement mode transistor.
        3
                       That's really the purpose of the p-type
            region under the gate.
        4
                                 MR. DOSHI: All right. Let's go
11:36
        5
        6
                       off the record.
        7
                       (Whereupon, the deposition recessed for
            lunch at 11:36 a.m.)
        8
        9
       10
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|       | 1  | AFTERNOON SESSION                               |
|-------|----|---|
|       | 2  | (12:28 p.m.)                                    |
|       | 3  | BY MR. DOSHI:                                   |
|       | 4  | Q. Welcome back, Dr. Shealy.                    |
| 12:28 | 5  | A. Thank you.                                   |
|       | 6  | Q. We went to can we go to this is              |
|       | 7  | Exhibit 1003, your declaration. And go to       |
|       | 8  | Exhibit 1020 I mean, I'm sorry Paragraph        |
|       | 9  | A. This is the '347 still?                      |
| 12:29 | 10 | Q. Yes yeah.                                    |
|       | 11 | It's Page 53. It's Paragraph 100.               |
|       | 12 | At the bottom there, you cite Sheppard.         |
|       | 13 | And this is in relation to the enhancement mode |
|       | 14 | issue.  |
| 12:29 | 15 | And does Sheppard use the term                  |
|       | 16 | "enhancement mode"?                             |
|       | 17 | A. I don't recall.                              |
|       | 18 | Q. Okay.  |
|       | 19 | A. It's been a while since I've read            |
| 12:29 | 20 | Sheppard.                                       |
|       | 21 | MR. DOSHI: Okay.                                |
|       | 22 | All right. I'm handing you                      |
|       | 23 | what's been previously marked as                |
|       | 24 | Exhibit 1021.                                   |
| 12:30 | 25 | (Whereupon, Exhibit 1021, previously            |
|       |    |   |

```
12:30
        1
            marked, was presented to the witness.)
        2
            BY MR. DOSHI:
        3
                 0.
                       And do you recognize this document?
        4
                       Yes. This is Sheppard.
                 Α.
12:31
                       And if you look at....
        5
                 Q.
                       On Page 53, you cite to Figure 1F.
        6
        7
                       And 1F seems --
        8
                 Α.
                       Yes.
                       -- to look a lot like Saxler's 1A.
        9
                 Q.
12:31
       10
                       Do you agree?
       11
                                    (Pause.)
       12
                       It seems to be nearly identical.
                 Α.
       13
                 Q.
                       Okay.
       14
                                    (Pause.)
12:33
       15
                 Q.
                       Thanks for bearing with me. I lost my
       16
            place here.
       17
                       All right. Let's switch topics a little
       18
            bit.
       19
                       Paragraph 95 of '347, which is on Page 50,
12:34
       20
            you have -- you refer to Beach. Correct?
       21
                 Α.
                       Correct.
       22
                                 MR. DOSHI:
                                              Okay.
       23
                       (Whereupon, Exhibit 1008, previously
       24
            marked, was presented to the witness.)
12:34
       25
                 Q.
                       I'm handing you what's been previously
```

| 12:34 | 1  | marked as 1008.                                  |
|-------|----|--|
|       | 2  | A. Okay. Thank you.                              |
|       | 3  | Q. All right. And that's Beach yes?              |
|       | 4  | A. Yes, it is.                                   |
| 12:35 | 5  | Q. Okay. And in 95, you rely on Beach for an     |
|       | 6  | alleged self-aligned etching technique.          |
|       | 7  | Is that right?                                   |
|       | 8  | A. That's correct.                               |
|       | 9  | Q. And in Paragraph 96 on Page 51 of your        |
| 12:35 | 10 | declaration, Beach does not disclose horizontal  |
|       | 11 | ledges. Right?                                   |
|       | 12 | A. That's correct.                               |
|       | 13 | Q. Okay. And Beach Figure 1 doesn't disclose     |
|       | 14 | side surfaces that extend horizontally. Right?   |
| 12:36 | 15 | A. What Beach figure shows is a you know,        |
|       | 16 | it's drawn as a vertical wall. It's an idealized |
|       | 17 | drawing, of course.                              |
|       | 18 | Well, one would expect it to have some           |
|       | 19 | curvature.                                       |
| 12:37 | 20 | Q. And that is I think you use the word          |
|       | 21 | "machine tolerance" in your declaration.         |
|       | 22 | Is that right?                                   |
|       | 23 | A. You might want to point me to that. I         |
|       | 24 | don't remember using that term.                  |
| 12:37 | 25 | Q. Okay. "Manufacturing tolerances," maybe?      |

| 12:37 | 1  | A. That I remember, yeah.                            |
|-------|----|--|
|       | 2  | Q. Okay. And is that why you would are               |
|       | 3  | the manufacturing tolerances why you would why       |
|       | 4  | you it's your opinion that a person of ordinary      |
| 12:38 | 5  | skill in the art would have understood Beach to have |
|       | 6  | some slope to its sidewalls?                         |
|       | 7  | MS. SPECHT: Objection; vague.                        |
|       | 8  | A. Beach is used for the self-aligned                |
|       | 9  | process. And the shape of the wall is not really     |
| 12:38 | 10 | relevant to the way it's used in the combination.    |
|       | 11 | Q. Okay. I'm going to switch to your other           |
|       | 12 | declaration. So this is '355.                        |
|       | 13 | This is for 1482 1382 1884.                          |
|       | 14 | I'm sorry. Third time's a charm.                     |
| 12:41 | 15 | Okay. And I'm on Page 34.                            |
|       | 16 | And there you have petitioner's claim                |
|       | 17 | construction. Do you see that, up at the top of      |
|       | 18 | A. Yes.  |
|       | 19 | Q Page 34?   |
| 12:42 | 20 | And you use that for your analysis?                  |
|       | 21 | Well, let me rephrase that.                          |
|       | 22 | You use that in your analysis, that claim            |
|       | 23 | construction.  |
|       | 24 | Is that right?                                       |
| 12:42 | 25 | A. Yes. But I we considered both                     |

| 12:42 | 1  | constructions. And the patents are invalid under |
|-------|----|--|
|       | 2  | both construction.                               |
|       | 3  | Q. Okay. And this relates to the                 |
|       | 4  | substantially this relates to side surfaces      |
| 12:42 | 5  | extending.                                       |
|       | 6  | Is that right?                                   |
|       | 7  | A. Yes.  |
|       | 8  | Q. Okay. And here you say that:                  |
|       | 9  | The bottom of the p-type                         |
| 12:42 | 10 | gate material is more than 10%                   |
|       | 11 | wider than the top of the                        |
|       | 12 | material.  |
|       | 13 | Right?   |
|       | 14 | A. That's what yes, that's what's there.         |
| 12:42 | 15 | Q. Okay. And is in your opinion, is 10%          |
|       | 16 | within manufacturing tolerance?                  |
|       | 17 | A. I think you need to explain that a little     |
|       | 18 | better.  |
|       | 19 | Q. Okay. So you used the term "manufacturing     |
| 12:43 | 20 | tolerance" in your declaration. Right?           |
|       | 21 | A. "Manufacturing" and "alignment accuracy"      |
|       | 22 | or something along those lines.                  |
|       | 23 | Q. Okay. And I'm just trying to understand       |
|       | 24 | how much of a variation would that be, in your   |
| 12:43 | 25 | opinion, in terms of                             |

|       | 1  |   |
|-------|----|---|
| 12:43 | 1  | A. 10 percent?                                      |
|       | 2  | Q. Yeah.  |
|       | 3  | A. Well, I still don't know the context of          |
|       | 4  | the question. I'm not quite sure what you're asking |
| 12:43 | 5  | me to   |
|       | 6  | Q. Okay. Let's go back to Exhibit 2002,             |
|       | 7  | which I'm handing you back.                         |
|       | 8  | A. Okay.  |
|       | 9  | Q. And in Panel B, you said that there would        |
| 12:44 | 10 | be some sloping of the sidewalls. Correct?          |
|       | 11 | A. Yes.   |
|       | 12 | Q. All right. And you said that's a function        |
|       | 13 | of the etching process. Right?                      |
|       | 14 | A. Yes.   |
| 12:44 | 15 | Q. Okay. How much of a tolerance is there           |
|       | 16 | for the chemicals or the etching processes that are |
|       | 17 | taking place in Saxler, for example?                |
|       | 18 | MS. SPECHT: Objection; form.                        |
|       | 19 | A. The trouble I'm having is the use of the         |
| 12:44 | 20 | word "tolerance."                                   |
|       | 21 | I mean, how to what extent can these                |
|       | 22 | sidewalls extend? is that?                          |
|       | 23 | That depends entirely. That can be                  |
|       | 24 | vary quite a bit by the etching process.            |
| 12:45 | 25 | Okay. You never get, you know, near                 |

| 12:45 | 1  | vertical. There's always some slope.                 |
|-------|----|--|
|       | 2  | But it can be exaggerated, depending on              |
|       | 3  | how you tune the etching process.                    |
|       | 4  | Q. All right. If you're trying to etch               |
| 12:47 | 5  | vertical sidewalls, how much wider would you expect  |
|       | 6  | the bottom of the material to be than the top, based |
|       | 7  | on the manufacturing tolerances that you describe in |
|       | 8  | your declaration?                                    |
|       | 9  | A. I guess the tolerance to me means the             |
| 12:47 | 10 | variation from one you know, if you do it 100        |
|       | 11 | times, how tight is the distribution?                |
|       | 12 | Q. I see.  |
|       | 13 | A. Is that?  |
|       | 14 | Q. Okay. So Paragraph 91 no, page 91                 |
| 12:47 | 15 | of '335, the same one.                               |
|       | 16 | A. Okay.   |
|       | 17 | (Pause.)   |
|       | 18 | Q. You know what, Dr. Shealy I'm sorry               |
|       | 19 | forget that.   |
| 12:48 | 20 | A. Okay.   |
|       | 21 | MR. DOSHI: We can go off the                         |
|       | 22 | record.  |
|       | 23 | (Whereupon, a recess was taken                       |
|       | 24 | from 12:48 p.m. until 12:50 p.m.)                    |
| 12:48 | 25 | (Whereupon, Exhibit 1009, previously                 |
|       |    |  |

| 12:48 | 1  | marked, was presented to the witness.)          |
|-------|----|---|
|       | 2  | BY MR. DOSHI:                                   |
|       | 3  | Q. I'm handing you what's been previously       |
|       | 4  | marked as Exhibit 1009.                         |
| 12:50 | 5  | And that is Shenoy, right?                      |
|       | 6  | A. Yes.   |
|       | 7  | Q. Okay. So do you understand Shenoy to be a    |
|       | 8  | hypothetical model?                             |
|       | 9  | A. Shenoy has a model in it. And the Board      |
| 12:51 | 10 | had a few comments on Shenoy, which I'd like to |
|       | 11 | address.  |
|       | 12 | Can I do that now?                              |
|       | 13 | Q. We can get there.                            |
|       | 14 | A. Okay.  |
| 12:51 | 15 | Q. And then, Shenoy teaches an isotropic        |
|       | 16 | etching process. Right?                         |
|       | 17 | A. Yes.   |
|       | 18 | Q. What is "isotropic," in your in your         |
|       | 19 | opinion?  |
| 12:51 | 20 | A. It means the material you're etching         |
|       | 21 | etches at the same rate in all directions.      |
|       | 22 | Q. Okay. And what are the materials that        |
|       | 23 | arewhat are the materials that are employed by  |
|       | 24 | Shenoy or that are being etched in Shenoy?      |
| 12:51 | 25 | A. It's a metal film.                           |

| 12:52 | 1  | Q. Um-hum. And it's etching to two films, or      |
|-------|----|---|
|       | 2  | one?  |
|       | 3  | A. Just one.                                      |
|       | 4  | Q. Okay. And there's an insulator at the          |
| 12:52 | 5  | bottom. Correct?                                  |
|       | 6  | A. Correct.                                       |
|       | 7  | Q. Okay. Does that spread the etching in the      |
|       | 8  | horizontal way?                                   |
|       | 9  | A. If the   |
| 12:52 | 10 | Whatever it does in this case.                    |
|       | 11 | But whatever is under it, if it doesn't           |
|       | 12 | etch, it will enhance the sideways etching or the |
|       | 13 | "undercut," if you like.                          |
|       | 14 | Q. "Undercut" meaning under the photoresist?      |
| 12:52 | 15 | A. Yes. It's shown by "U" in this diagram,        |
|       | 16 | Figure 1.   |
|       | 17 | Q. Okay. So                                       |
|       | 18 | (Pause.)  |
|       | 19 | MR. DOSHI: I'm handing you what                   |
| 12:53 | 20 | has been previously marked as                     |
|       | 21 | Exhibit 1020.                                     |
|       | 22 | (Whereupon, Exhibit 1020, previously              |
|       | 23 | marked, was presented to the witness.)            |
|       | 24 | BY MR. DOSHI:                                     |
| 12:55 | 25 | Q. And do you recognize the document?             |
|       |    |   |

| 12:55 | 1  | A. Yes.  |
|-------|----|--|
|       | 2  | Q. And what is it?                                 |
|       | 3  | A. Excuse me?                                      |
|       | 4  | Q. What do you recognize it to be?                 |
| 12:55 | 5  | A. The Uemoto reference, which is referenced       |
|       | 6  | in the declaration.                                |
|       | 7  | Q. Okay. And turning to Figure 5, which I          |
|       | 8  | believe you referenced in your declaration do you  |
|       | 9  | see that?  |
| 12:55 | 10 | A. Yes.  |
|       | 11 | Q. Okay. And Page 101 of the '335                  |
|       | 12 | declaration, I think you blow that image up a bit? |
|       | 13 | A. Yes.  |
|       | 14 | Q. And does Uemoto show substantially equal        |
| 12:56 | 15 | widths?  |
|       | 16 | A. Could you explain which widths on the           |
|       | 17 | diagram you're talking about.                      |
|       | 18 | Q. Sure. The ledges, basically.                    |
|       | 19 | A. Below the brighter metal?                       |
| 12:56 | 20 | Q. Correct, yeah.                                  |
|       | 21 | A. I would not call those "substantially           |
|       | 22 | equal ledges," no.                                 |
|       | 23 | Q. Okay. Let's go back to Beach.                   |
|       | 24 | Sorry I'm jumping around a little bit.             |
| 12:57 | 25 | I asked you previously whether you rely on         |

| 12:57 | 1  | this or I think you testified that this you         |
|-------|----|---|
|       | 2  | relied on this for the self-alignment piece.        |
|       | 3  | Is that right?                                      |
|       | 4  | A. Yes.   |
| 12:57 | 5  | Q. Okay. And when we say "self" when you            |
|       | 6  | say "self-alignment," are you referring to and      |
|       | 7  | I'm looking at Figure 1, which you rely on in your  |
|       | 8  | declaration.  |
|       | 9  | Is that right?                                      |
| 12:57 | 10 | A. Yes.   |
|       | 11 | Q. And 26 and 24 are etched at the same time.       |
|       | 12 | Right?  |
|       | 13 | A. Yes.   |
|       | 14 | Q. Okay. And that presupposes that 26 and 24        |
| 12:58 | 15 | have been formed before the etching process. Right? |
|       | 16 | A. Yes.   |
|       | 17 | Q. Okay. And 24 is the gate electrode?              |
|       | 18 | A. Let's double-check that.                         |
|       | 19 | (Witness reading.)                                  |
| 12:58 | 20 | A. 24 is the gate metal.                            |
|       | 21 | Q. Which serves as the electrode?                   |
|       | 22 | A. Yes.   |
|       | 23 | MR. DOSHI: Let's take ten                           |
|       | 24 | minutes. I might be wrapping up.                    |
| 12:59 | 25 | Off the record.                                     |
|       |    |   |

| 12:59 | 1  | (Whereupon, a recess was taken                      |
|-------|----|---|
|       | 2  | from 12:59 p.m. until 1:11 p.m.)                    |
|       | 3  | MR. DOSHI: I'll pass the                            |
|       | 4  | witness.  |
| 01:11 | 5  | MS. SPECHT: Then we're going to                     |
|       | 6  | take one more break.                                |
|       | 7  | MR. DOSHI: Say it again?                            |
|       | 8  | MS. SPECHT: Ten minutes.                            |
|       | 9  | MR. DOSHI: Oh, okay.                                |
| 01:25 | 10 | (Whereupon, a recess was taken                      |
|       | 11 | from 1:11 p.m. until 1:25 p.m.)                     |
|       | 12 | MS. SPECHT: Ready?                                  |
|       | 13 | MR. DOSHI: Yep.                                     |
|       | 14 | MS. SPECHT: All right.                              |
| 01:25 | 15 | EXAMINATION   |
|       | 16 | BY MS. SPECHT:                                      |
|       | 17 | Q. Okay, Dr. Shealy. Do you recall, just a          |
|       | 18 | moment ago, counsel for EPC asking you about the    |
|       | 19 | Shenoy reference, which is Exhibit 1020?            |
| 01:26 | 20 | A. 1009.  |
|       | 21 | Q. Exhibit 1009, yes.                               |
|       | 22 | A. Yes, I do recall.                                |
|       | 23 | Q. And you mentioned during your testimony          |
|       | 24 | you actually asked permission during your testimony |
| 01:26 | 25 | to explain the model in Shenoy.                     |
|       |    | ·   |

| 01:26 | 1  | Do you remember asking that?                         |
|-------|----|--|
|       | 2  | A. Yes.  |
|       | 3  | Q. And since you were denied your request to         |
|       | 4  | explain Shenoy's model, can you explain Shenoy's     |
| 01:26 | 5  | model now?   |
|       | 6  | A. Yes. Shenoy describes isotropic etching           |
|       | 7  | through a photoresist window.                        |
|       | 8  | So a POSITA would know that isotropic                |
|       | 9  | etching can be done a variety of ways, and one way   |
| 01:27 | 10 | is the example given in Shenoy: EMM.                 |
|       | 11 | There's other techniques of isotropic                |
|       | 12 | etching which involve using liquid metal etches that |
|       | 13 | are especially formulated for specific metals.       |
|       | 14 | And they've been around a very long time,            |
| 01:27 | 15 | common metals that would be used in a process like   |
|       | 16 | this nickel, aluminum, tungsten. There's a long      |
|       | 17 | list of solutions that have been developed for this  |
|       | 18 | purpose.   |
|       | 19 | And these solutions, unlike the technique            |
| 01:27 | 20 | used in Shenoy, do not require an external applied   |
|       | 21 | potential.   |
|       | 22 | So in any case, Shenoy's model also                  |
|       | 23 | possesses symmetry. And that same symmetry is        |
|       | 24 | present in the Yoshida and Saxler reference.         |
| 01:28 | 25 | So the Board was interested in symmetry              |

| 01:28 | 1  | because it was listed under "Assumptions."           |
|-------|----|--|
|       | 2  | And the if you're because symmetry                   |
|       | 3  | is present in the structure, symmetry is a valid     |
|       | 4  | assumption. It doesn't need to be assumed, but it    |
| 01:28 | 5  | cuts down the number of computations to complete the |
|       | 6  | model.   |
|       | 7  | So symmetry is built in by the structure             |
|       | 8  | that's being modeled. Okay? And it mirrors the       |
|       | 9  | symmetry of, as I said, Yoshida and Saxler.          |
| 01:29 | 10 | The other point about Shenoy is: The                 |
|       | 11 | metal film that's being etched is under the          |
|       | 12 | insulator or is over the insulator. The              |
|       | 13 | insulator's under the metal.                         |
|       | 14 | When we make this combination and of                 |
| 01:29 | 15 | Yoshida, Saxler, or vice versa, with Beach           |
|       | 16 | Beach is used for the self-alignment.                |
|       | 17 | Shenoy is used for the undercut.                     |
|       | 18 | So when we make this combination, there's            |
|       | 19 | not a insulator under the metal, there's a           |
| 01:29 | 20 | semiconductor layer, as the Board pointed out.       |
|       | 21 | In our case, it's either a p-type gallium            |
|       | 22 | nitride or it could be p-type aluminum gallium       |
|       | 23 | nitride cap capping layer in the terminology of      |
|       | 24 | Saxler.  |
| 01:30 | 25 | However, the metal that sits on that                 |

| 01:30 | 1  | top of that semiconductor surface and the            |
|-------|----|--|
|       | 2  | sidewalls, presumably, have already been exposed     |
|       | 3  | those surfaces deplete the semiconductor of holes.   |
|       | 4  | This is a p-type semiconductor dope of               |
| 01:30 | 5  | magnesium, and it would normally have holes. But     |
|       | 6  | because of these side surfaces, the holes are        |
|       | 7  | depleted away from the surface where the etching is  |
|       | 8  | occurring.   |
|       | 9  | And what that means is, is that the                  |
| 01:30 | 10 | semiconductor layer behaves as an insulator just     |
|       | 11 | like Shenoy's structure, because there are no mobile |
|       | 12 | charges near the etching region in the               |
|       | 13 | semiconductor. Okay?                                 |
|       | 14 | The other point that affects the edge is             |
| 01:31 | 15 | that the fact that and the majority of these         |
|       | 16 | liquid metal etches that I've referred to, they      |
|       | 17 | don't touch the gallium nitride.                     |
|       | 18 | Gallium nitride is a pretty tough material           |
|       | 19 | to etch, and a lot of these etches will not etch it. |
| 01:31 | 20 | So that that's, again, like Shenoy:                  |
|       | 21 | The insulator is not being etched in Shenoy. In      |
|       | 22 | this case, the p-type cap below the metal was not    |
|       | 23 | being etched when we make the combination.           |
|       | 24 | Okay. The other thing the Board had to               |
| 01:31 | 25 | say was, they commented on Shenoy's model does       |

| 01:31 | 1  | focus on the angle of the metal that results from   |
|-------|----|---|
|       | 2  | the etch, which is related to the angle of the      |
|       | 3  | photoresist.  |
|       | 4  | The angle of the metal is not what we're            |
| 01:32 | 5  | relying for in this combination.                    |
|       | 6  | We're using Shenoy to provide the undercut          |
|       | 7  | of the metal. Okay? So we're not relying on it for  |
|       | 8  | the for anything related to the mask-wall angle.    |
|       | 9  | The undercut, as shown in Shenoy, is not            |
| 01:32 | 10 | really a strong function of that angle anyway. So   |
|       | 11 | we're relying on it for undercut. So                |
|       | 12 | And the other comment they made is                  |
|       | 13 | something about the film thickness.                 |
|       | 14 | I say "something" because they have                 |
| 01:32 | 15 | concerns. And so, I'm not sure exactly what they    |
|       | 16 | are. But the film thickness, when you do an         |
|       | 17 | undercut like this as you increase the film         |
|       | 18 | thickness, the undercut increases. That's the major |
|       | 19 | effect of the film thickness.                       |
| 01:32 | 20 | So the undercut, in general, is on the              |
|       | 21 | order that lateral dimension, on the order of the   |
|       | 22 | thickness of the metal not exactly, but it's on     |
|       | 23 | the same order.                                     |
|       | 24 | I don't know if that answered your                  |
| 01:33 | 25 | question.   |

|       | 1  |   |
|-------|----|---|
| 01:33 | 1  | Q. That answers my question very thoroughly.        |
|       | 2  | But I do have a couple of followups.                |
|       | 3  | So at the very beginning of your earlier            |
|       | 4  | answer, you mentioned that Shenoy had techniques    |
| 01:33 | 5  | other than EMM.                                     |
|       | 6  | Is that what you testified to?                      |
|       | 7  | A. Well, when a                                     |
|       | 8  | MR. DOSHI: Objection.                               |
|       | 9  | A. When a person of skill looks at Shenoy,          |
| 01:33 | 10 | they're going to see that there are many other      |
|       | 11 | isotropic etching techniques that can benefit from  |
|       | 12 | Shenoy's work I mean, that's one way to say it.     |
|       | 13 | And furthermore, the EMM technique that             |
|       | 14 | Shenoy employs, there's nothing wrong with applying |
| 01:33 | 15 | that in our combination with Yoshida and Saxler and |
|       | 16 | Beach and Shenoy. The EMM technique will work fine  |
|       | 17 | to do that. It's an option for the fabrication      |
|       | 18 | engineer.   |
|       | 19 | MS. SPECHT: So let's switch                         |
| 01:34 | 20 | gears and talk about Exhibit 2002 that you          |
|       | 21 | drew for EPC's counsel earlier.                     |
|       | 22 | So we can just grab that and                        |
|       | 23 | go ahead and pass 2003 as well. And I'll            |
|       | 24 | hand him that one.                                  |
| 01:34 | 25 | Thank you.  |
|       |    |   |

| 01:34 | 1  | BY MS. SPECHT:                                       |
|-------|----|--|
|       | 2  | Q. So Dr. Shealy, looking at 2002, does              |
|       | 3  | Step~B apply to the prior art in this case?          |
|       | 4  | A. Yes.  |
| 01:34 | 5  | Q. Are there any references that you've              |
|       | 6  | relied on in this case that Step B is not            |
|       | 7  | representative of?                                   |
|       | 8  | A. No. I mean, you said, Are there any               |
|       | 9  | references that represent something other than this? |
| 01:35 | 10 | The only way to etch these surfaces in               |
|       | 11 | these references is a plasma etch, and all plasma    |
|       | 12 | etches produce this sloped sidewall.                 |
|       | 13 | Q. And can you explain what Step C is as well        |
|       | 14 | and which references Step C is representative of.    |
| 01:35 | 15 | A. Step C has been known in the art for quite        |
|       | 16 | a while. It's a it's called a crystallographic       |
|       | 17 | etch. And there are specific etch chemistries used   |
|       | 18 | to do it.  |
|       | 19 | But it will expose those it can expose               |
| 01:35 | 20 | a perfect 90-degree plane because it's based on the  |
|       | 21 | crystal itself.                                      |
|       | 22 | And so, it's this is you know,                       |
|       | 23 | literally, this is an exposed plane with not many    |
|       | 24 | atomic steps in it. So that's why we say it's        |
| 01:36 | 25 | almost a perfect 90-degree angle.                    |

| 01:36 | 1  | The other part of your question: This               |
|-------|----|---|
|       | 2  | does not appear in any of the art in this case.     |
|       | 3  | Q. Let's now talk about Exhibit 2003, which         |
|       |    |   |
|       | 4  | I'm going to pass to you as well.                   |
| 01:36 | 5  | Exhibit 2003 is based on Figure 1B?                 |
|       | 6  | A. Yes.   |
|       | 7  | Q. Of the Saxler reference. Right?                  |
|       | 8  | A. Yes.   |
|       | 9  | Q. And do you recall asking EPC's counsel if        |
| 01:36 | 10 | you could instead draw a figure related to your     |
|       | 11 | modified 1A of Saxler's reference?                  |
|       | 12 | A. Yes.   |
|       | 13 | Q. Can you draw a representative diagram            |
|       | 14 | using your modified 1A?                             |
| 01:37 | 15 | A. Okay. So we need to start with the               |
|       | 16 | modified  |
|       | 17 | I'll label this "A" in this diagram.                |
|       | 18 | All I'm doing in the "A" illustration is            |
|       | 19 | attempt to reproduce the in fact, it wouldn't be    |
| 01:37 | 20 | a bad idea to look at it.                           |
|       | 21 | (Witness reading.)                                  |
|       | 22 | A. Okay. This is the simplified diagram of          |
|       | 23 | the modified Figure 1A, where the recess is removed |
|       | 24 | and p-dopants are added in the capping layer.       |
| 01:38 | 25 | And so, now we need to identify the                 |
| 01:30 | 43 | And so, now we need to identity the                 |

| 01:38 | 1  | regions where the sloped walls are.                  |
|-------|----|--|
|       | 2  | And now we'll draw the in                            |
|       | 3  | Illustration~B, we'll draw what was where is         |
|       | 4  | the other one? we'll draw the off condition to       |
| 01:39 | 5  | correspond to the other diagram.                     |
|       | 6  | Okay. So again, we have an electron gas              |
|       | 7  | underneath the source and drain contact.             |
|       | 8  | As you enter the slope part of the region,           |
|       | 9  | you're picking up negative charge. So that causes a  |
| 01:40 | 10 | gradual depletion of the electrons out of the 2D gas |
|       | 11 | in that region.                                      |
|       | 12 | And so, basically, it looks very similar             |
|       | 13 | to the other diagram of 1A, except the there's a     |
|       | 14 | broader transition because of the sloped regions on  |
| 01:40 | 15 | that p-type cap.                                     |
|       | 16 | That's assuming it's, more or less,                  |
|       | 17 | uniformly doped which is the way it appears in       |
|       | 18 | Yoshida anyway, by the way.                          |
|       | 19 | Okay. And then there's one other diagram             |
| 01:40 | 20 | we can make we'll call "C."                          |
|       | 21 | And this is for the Ahn condition. Both              |
|       | 22 | are for low drain bias.                              |
|       | 23 | Okay. So in this case, you have a 2D                 |
|       | 24 | electron gas under the source and drain contacts,    |
| 01:41 | 25 | just like we had before.                             |

| 01:41 | 1  | And now we'll assume that we're driving              |
|-------|----|--|
|       | 2  | the gate to a reasonable level, where we've actually |
|       | 3  | increased the concentration over what's in the       |
|       | 4  | over what's in the under the contacts.               |
| 01:41 | 5  | And so, it looks something like this                 |
|       | 6  | (indicating).  |
|       | 7  | Very similar, except during in these                 |
|       | 8  | regions, the distribution of electrons is smeared    |
|       | 9  | out.   |
| 01:42 | 10 | So other than that, it's very similar.               |
|       | 11 | Q. And in the diagram that you've just drawn,        |
|       | 12 | which I'm going to label Exhibit 1032 in just a      |
|       | 13 | minute, is there a gap between the cap layer and the |
|       | 14 | Ohmic contacts?                                      |
| 01:42 | 15 | A. Yeah, I kind of I mean, it's a little             |
|       | 16 | more exaggerated than what it was in the original    |
|       | 17 | drawing. But it's basically the same.                |
|       | 18 | MS. SPECHT: Okay. So let's                           |
|       | 19 | mark that paper Petitioner's Exhibit 1032.           |
| 01:42 | 20 | And we'll use the same one in                        |
|       | 21 | both proceedings no need to put a                    |
|       | 22 | proceeding number on.                                |
|       | 23 | (Whereupon, Exhibit 1032 was marked for              |
|       | 24 | identification.)                                     |
| 01:42 | 25 | MS. SPECHT: And with that, pass                      |

| 01:42 | 1  | the witness.                                       |
|-------|----|--|
|       | 2  | FURTHER EXAMINATION                                |
|       | 3  | BY MR. DOSHI:                                      |
|       | 4  | Q. Just a couple of questions.                     |
| 01:42 | 5  | You were talking about Shenoy and the              |
|       | 6  | insulator. Right?                                  |
|       | 7  | A. Yes.  |
|       | 8  | Q. Okay. And is there an insulator in              |
|       | 9  | Saxler?  |
| 01:42 | 10 | A. The   |
|       | 11 | Semiconductors behave as conductors                |
|       | 12 | sometimes and insulators in others.                |
|       | 13 | If you deplete the mobile charge out of            |
|       | 14 | the semiconductor, it behaves as an insulator. It  |
| 01:43 | 15 | won't support any current flow, because there's no |
|       | 16 | mobile charge in it.                               |
|       | 17 | And that's what happens when you surround          |
|       | 18 | this p-type layer with surfaces and a metal.       |
|       | 19 | Metal depletes mobile charge. And a                |
| 01:43 | 20 | surface terminated with air or even a liquid       |
|       | 21 | etch, for that matter will also deplete the        |
|       | 22 | mobile charge.                                     |
|       | 23 | So that layer is more or less devoid of            |
|       | 24 | mobile charge. So it behaves like an insulator.    |
| 01:43 | 25 | Q. And what about the underlying barrier           |

| 01:43 | 1  | layer?  |
|-------|----|---|
|       | 2  | A. The underlying barrier layer has it              |
|       | 3  | basically is used to confine electrons below it.    |
|       | 4  | It's devoid there's no charge in that layer.        |
| 01:43 | 5  | What it's there for is to provide a                 |
|       | 6  | potential barrier to confine the electrons below    |
|       | 7  | that barrier.                                       |
|       | 8  | Q. Would it serve as an insulator?                  |
|       | 9  | A. What's that?                                     |
| 01:44 | 10 | Q. Would the barrier layer serve as an              |
|       | 11 | insulator?  |
|       | 12 | A. It would not conduct if you there's no           |
|       | 13 | mobile charge. So in that sense, you could say it   |
|       | 14 | behaves like an insulator.                          |
| 01:44 | 15 | Most people wouldn't call a semiconductor           |
|       | 16 | an insulator. But they certainly can behave like an |
|       | 17 | insulator.  |
|       | 18 | Q. So you were saying that the etching              |
|       | 19 | process of Shenoy, it uses the insulator to spread  |
| 01:44 | 20 | the horizontal etching.                             |
|       | 21 | Is that is my understanding correct?                |
|       | 22 | A. The fact that it doesn't etch                    |
|       | 23 | Q. Yeah.  |
|       | 24 | A enhances the lateral etching.                     |
| 01:44 | 25 | Q. Well, isn't it going to etch the barrier         |

| 01:44 | 1  | layer, though?                                   |  |  |
|-------|----|--|--|--|
|       | 2  | A. No. The barrier layer is covered up.          |  |  |
|       | 3  | Q. With what?                                    |  |  |
|       | 4  | A. It's covered up with the when you do          |  |  |
| 01:45 | 5  | this gate processing, if the Ohmics are there,   |  |  |
|       | 6  | they're going to be covered up.                  |  |  |
|       | 7  | If it's done first, they're not there.           |  |  |
|       | 8  | But it's still that surface is going to be       |  |  |
|       | 9  | covered up.                                      |  |  |
| 01:45 | 10 | Q. Isn't there a cap between the p-n and the     |  |  |
|       | 11 | Ohmic contacts? Didn't you just testify to that? |  |  |
|       | 12 | A. Are we talking vertically?                    |  |  |
|       | 13 | Q. You were talking about 1A, right? right       |  |  |
|       | 14 | now  |  |  |
| 01:45 | 15 | A. Yeah.   |  |  |
|       | 16 | Q recently.                                      |  |  |
|       | 17 | And what I'm asking is the barrier               |  |  |
|       | 18 | layer  |  |  |
|       | 19 | A. Oh, no  |  |  |
| 01:45 | 20 | (Simultaneous speaking.)                         |  |  |
|       | 21 | A. No, there's there's no conduction             |  |  |
|       | 22 | there.   |  |  |
|       | 23 | And when you perform this process of             |  |  |
|       | 24 | etching this metal, this if you do Ohmic first,  |  |  |
| 01:45 | 25 | you're going to cover those up with a and you'll |  |  |

| 01:45 | 1  | cover them up with a you typically would cover it   |  |  |
|-------|----|---|--|--|
|       | 2  | up, just as you read in Yoshida, with SiO2. It's a  |  |  |
|       | 3  | very common material to                             |  |  |
|       | 4  | If you want to process something over here          |  |  |
| 01:45 | 5  | and have this not influence the process, you cover  |  |  |
|       | 6  | it up with an insulator.                            |  |  |
|       | 7  | Q. And when you cover it up, you're doing           |  |  |
|       | 8  | selective covering. Correct?                        |  |  |
|       | 9  | So you're using a masking process, in               |  |  |
| 01:46 | 10 | other words?  |  |  |
|       | 11 | A. You would have to it would take a                |  |  |
|       | 12 | masking process to open a window where you're going |  |  |
|       | 13 | to do the gate work and cover up the Ohmics.        |  |  |
|       | 14 | Q. So you'd have to put in the silicon              |  |  |
| 01:46 | 15 | oxide   |  |  |
|       | 16 | A. That's one way to do it, yeah.                   |  |  |
|       | 17 | Q and then you're going to etch the                 |  |  |
|       | 18 | window. Right?                                      |  |  |
|       | 19 | A. And the SiO2                                     |  |  |
| 01:46 | 20 | Q. Right.   |  |  |
|       | 21 | A to expose the gate region.                        |  |  |
|       | 22 | Q. Okay. And then you expose the gate               |  |  |
|       | 23 | region. Correct?                                    |  |  |
|       | 24 | A. Yeah.  |  |  |
| 01:46 | 25 | Q. All right. You do your etching process.          |  |  |

|       | 1  |                 |   |  |
|-------|----|-----------------|---|--|
| 01:46 | 1  | And then do you |   |  |
|       | 2  | A.              | You got to put the metal down first.      |  |
|       | 3  | Q.              | Okay. And then do you remove the silicon  |  |
|       | 4  | oxide?          |   |  |
| 01:46 | 5  | A.              | Yes.                                      |  |
|       | 6  |                 | MR. DOSHI: Okay. All right.               |  |
|       | 7  |                 | That's it.                                |  |
|       | 8  |                 | MS. SPECHT: No further                    |  |
|       | 9  |                 | questions on our side.                    |  |
| 01:46 | 10 |                 | MR. DOSHI: Okay.                          |  |
|       | 11 |                 | COURT REPORTER:                           |  |
|       | 12 |                 | Confidentiality? Read and sign?           |  |
|       | 13 |                 | Anything I need to know?                  |  |
|       | 14 |                 | MS. SPECHT: We'll say read and            |  |
| 01:46 | 15 |                 | sign, but                                 |  |
|       | 16 |                 | The Board doesn't really let you          |  |
|       | 17 |                 | read and sign, but we'll say we will just |  |
|       | 18 |                 | in case.                                  |  |
|       | 19 |                 | COURT REPORTER: Okay.                     |  |
| 01:46 | 20 |                 | MR. DOSHI: Off the record.                |  |
|       | 21 |                 | (Time noted: 1:46 p.m.)                   |  |
|       | 22 |                 |   |  |
|       | 23 |                 |   |  |
|       | 24 |                 |   |  |
|       | 25 |                 |   |  |
|       |    |                 |   |  |

| 1  | DEPONENT'S SIGNATURE                                |
|----|---|
| 2  |   |
| 3  | Please be advised I have read the                   |
| 4  | foregoing deposition, pages 1 through 110,          |
| 5  | inclusive. I hereby state there are:                |
| 6  | (Check one)   |
| 7  | No corrections                                      |
| 8  | Corrections per attached                            |
| 9  | corrections per decidence                           |
| 10 |   |
| 11 |   |
| 12 | JAMES RICHARD SHEALY, PH.D.                         |
| 13 |   |
| 14 | ( X ) Reading and signing was requested.            |
| 15 | ( ) Reading and signing was waived.                 |
| 16 | ( ) Reading and signing was not requested.          |
| 17 |   |
| 18 |   |
| 19 | Should the signature of the witness not             |
| 20 | be affixed to the deposition, the witness shall not |
| 21 | have availed himself of the opportunity to sign or  |
| 22 | the signature has been waived.                      |
| 23 |   |
| 24 | 000   |
| 25 |   |

| 1  | ERRATA SHEET                                 |
|----|--|
| 2  | NAME OF CASE: Innoscience, et al. v. EPC     |
| 3  | Corporation                                  |
| 4  | DATE OF DEPOSITION: May 16, 2024             |
| 5  | NAME OF WITNESS: JAMES RICHARD SHEALY, PH.D. |
| 6  | Reason Codes:                                |
| 7  | 1: To clarify the record.                    |
| 8  | 2: To conform to the facts.                  |
| 9  | 3: To correct transcription error.           |
| 10 | Page Line Reason                             |
| 11 | From to                                      |
| 12 | Page Line Reason                             |
| 13 | From to                                      |
| 14 | Page Line Reason                             |
| 15 | From to                                      |
| 16 | Page Line Reason                             |
| 17 | From to                                      |
| 18 | Page Line Reason                             |
| 19 | From to                                      |
| 20 | Page Line Reason                             |
| 21 | From to                                      |
| 22 |  |
| 23 |  |
| 24 | JAMES RICHARD SHEALY, PH.D. DATE             |
| 25 |  |
|    |  |

| 1  | DECLARATION UNDER PENALTY OF PERJURY               |
|----|--|
| 2  | I am the witness in the foregoing                  |
| 3  | deposition.  |
| 4  | I have read the foregoing deposition or            |
| 5  | have had read to me the foregoing deposition, and  |
| 6  | having made such changes and corrections as I      |
| 7  | desired, I certify that the same is true in my own |
| 8  | knowledge.   |
| 9  | I hereby declare under penalty of perjury          |
| 10 | that the foregoing is true and correct.            |
| 11 | In witness whereof, I hereby subscribe my          |
| 12 | name this, 2024.                                   |
| 13 |  |
| 14 |  |
| 15 | JAMES RICHARD SHEALY, PH.D.                        |
| 16 |  |
| 17 |  |
| 18 |  |
| 19 |  |
| 20 |  |
| 21 |  |
| 22 |  |
| 23 |  |
| 24 |  |
| 25 |  |

| 1  | CERTIFICATE  |
|----|--|
| 2  |  |
| 3  | I, SUSAN ASHE, a Registered Merit                    |
| 4  | Reporter and Notary Public, hereby certify that the  |
| 5  | foregoing is a true and accurate transcript of the   |
| 6  | deposition of said witness, who was first duly sworn |
| 7  | by me on the date and place hereinbefore set forth.  |
| 8  | I FURTHER CERTIFY that I am neither                  |
| 9  | attorney nor counsel, nor related to or employed by  |
| 10 | any of the parties to the action in which this       |
| 11 | deposition was taken, and further that I am not a    |
| 12 | relative or employee of any attorney or counsel      |
| 13 | employed in this action, nor am I financially        |
| 14 | interested in this case.                             |
| 15 | Dated this 20th day of May 2024.                     |
| 16 |  |
| 17 |  |
| 18 |  |
| 19 | Susan Ashe, Notary Public                            |
| 20 | for the Commonwealth of Virginia                     |
| 21 |  |
| 22 | My commission expires: January 31, 2027.             |
| 23 | Notary Registration Number: 100809.                  |
| 24 |  |
| 25 |  |

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